

# Using ECC Feedback to Guide Voltage Speculation in Low-Voltage Processors

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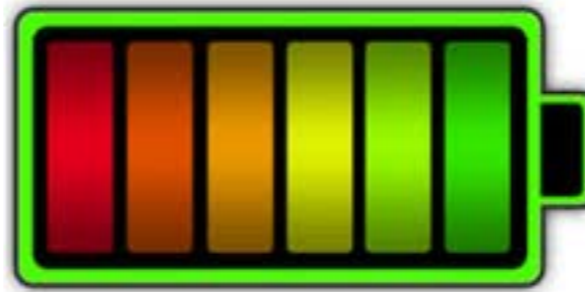


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# Energy Efficiency



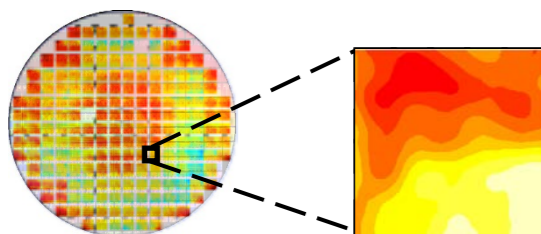
Energy efficiency is now crucial to all computing markets, especially in the growth areas: mobile and cloud computing.



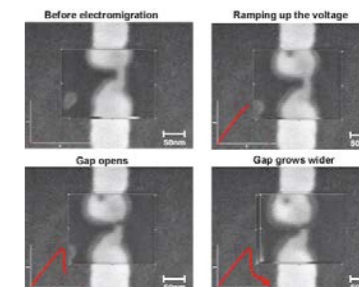


# Microprocessor Challenges

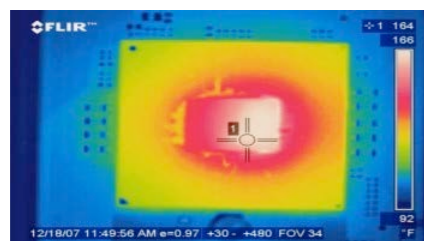
Process variation



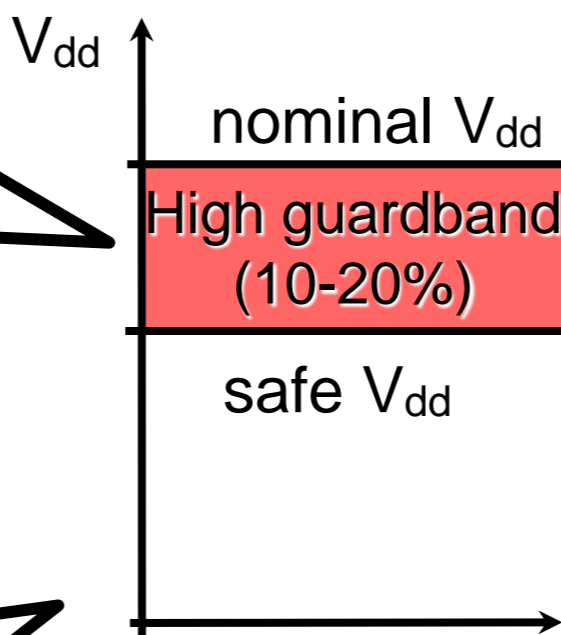
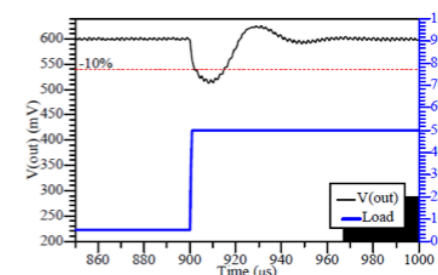
Circuit aging



Temperature



Voltage noise

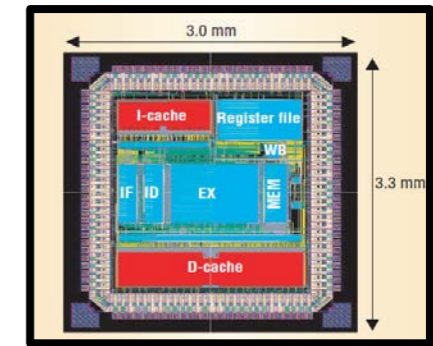


Energy inefficient

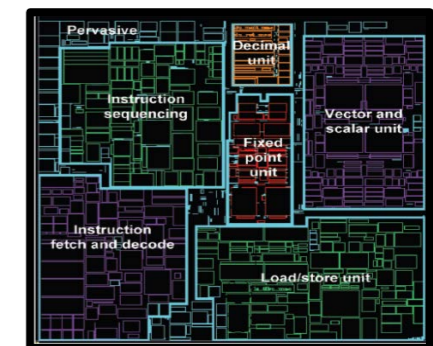


# Voltage Speculation

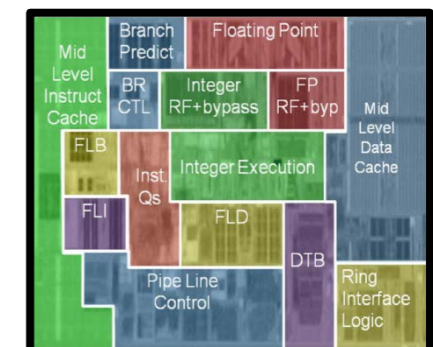
- Razor (Ernst et al. MICRO'03)
- Shadow latches detect/correct errors
- IBM POWER7 (Lefurgy et al. MICRO'11)
- Critical path monitors help avoid errors
- Itanium 9560 (Bacha and Teodorescu ISCA'13)
- ECC conservatively help avoid errors via software speculation



Razor



POWER7



Itanium 9560

# The Case for Low Voltage Speculation

- Commercial interest in low voltage for substantial energy savings



Intel Claremont solar chip

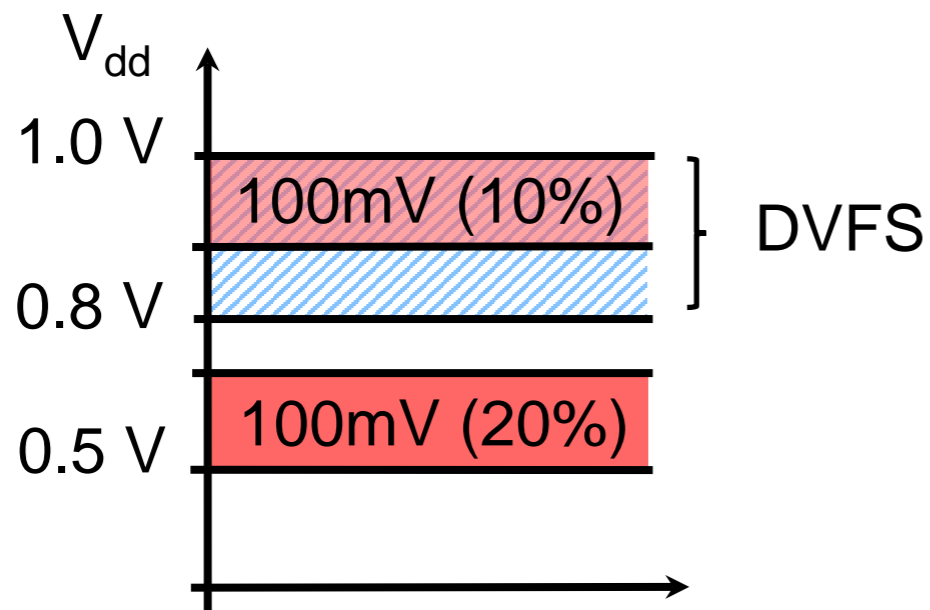


# The Case for Low Voltage Speculation

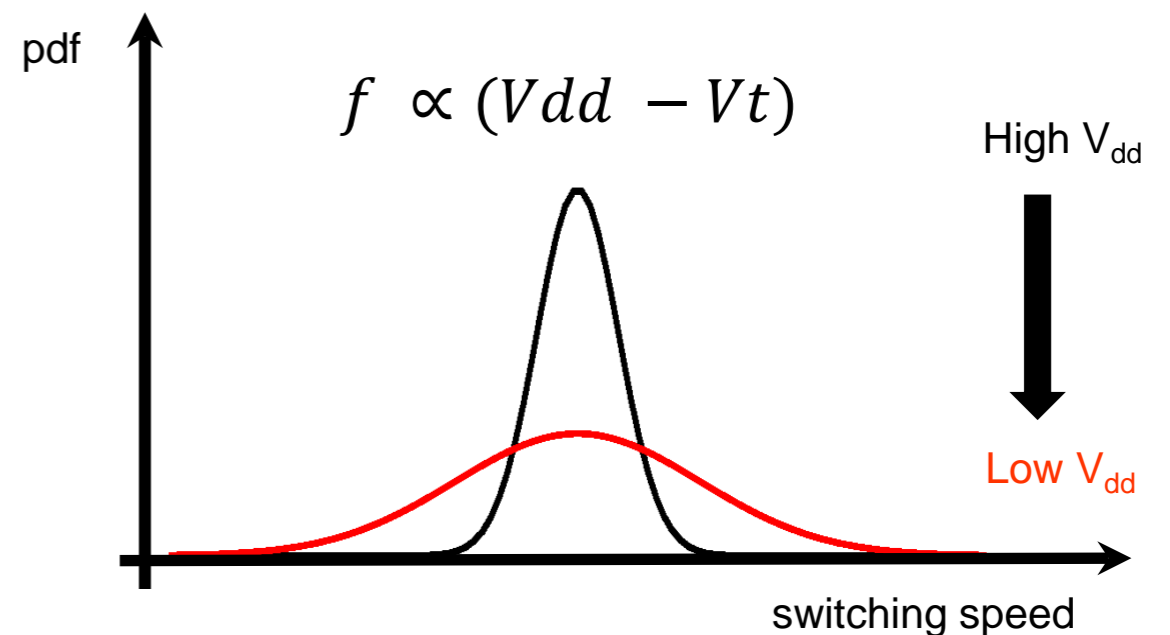
- Commercial interest in low voltage for substantial energy savings



Intel Claremont solar chip



Prohibitive guardbands



Amplified process variation effects



# Outline

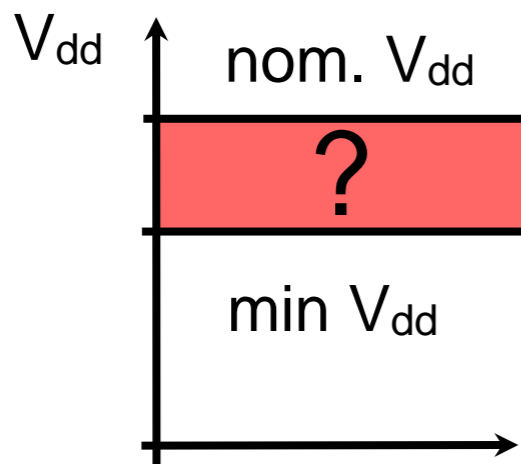
- Motivation
- ECC-based voltage speculation
- Experimental framework
- Evaluation



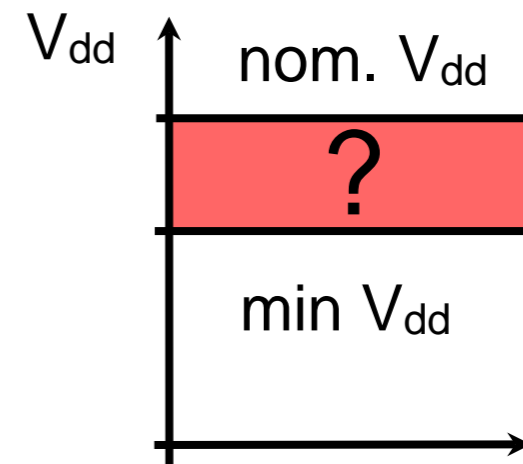
# Margin Opportunity at Low Voltage

- Margin exploration of 32nm 8-core CMP at two constant frequencies

2.53 GHz (High  $V_{dd}$ )

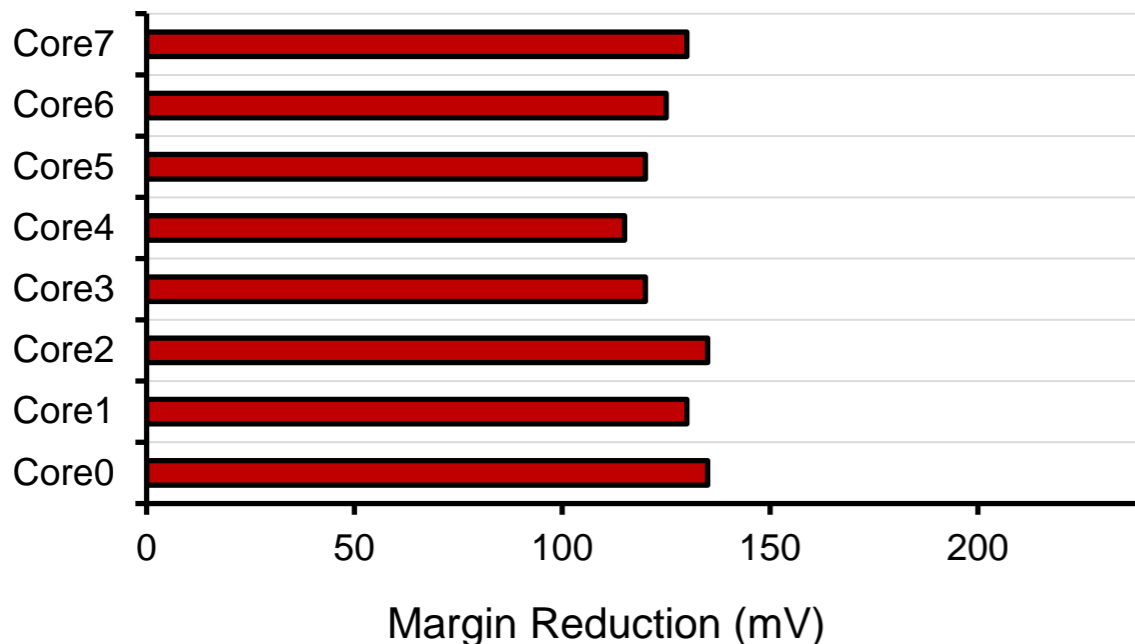


340 MHz (Low  $V_{dd}$ )

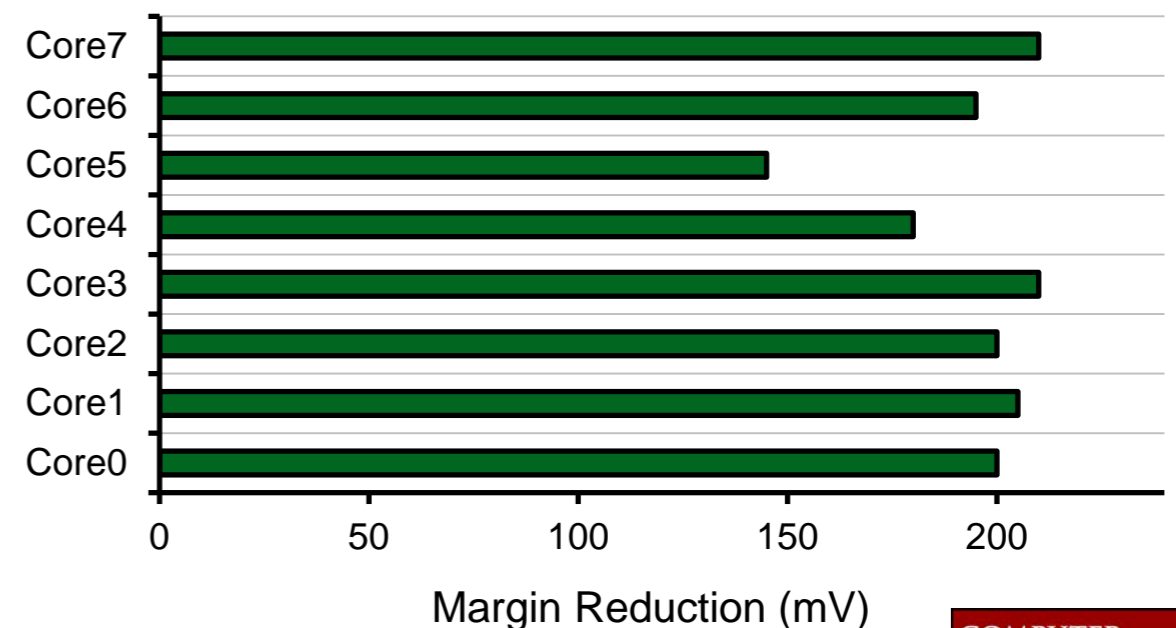


**60%  
More Margin**

**Margin at high Vdd (120mV)**



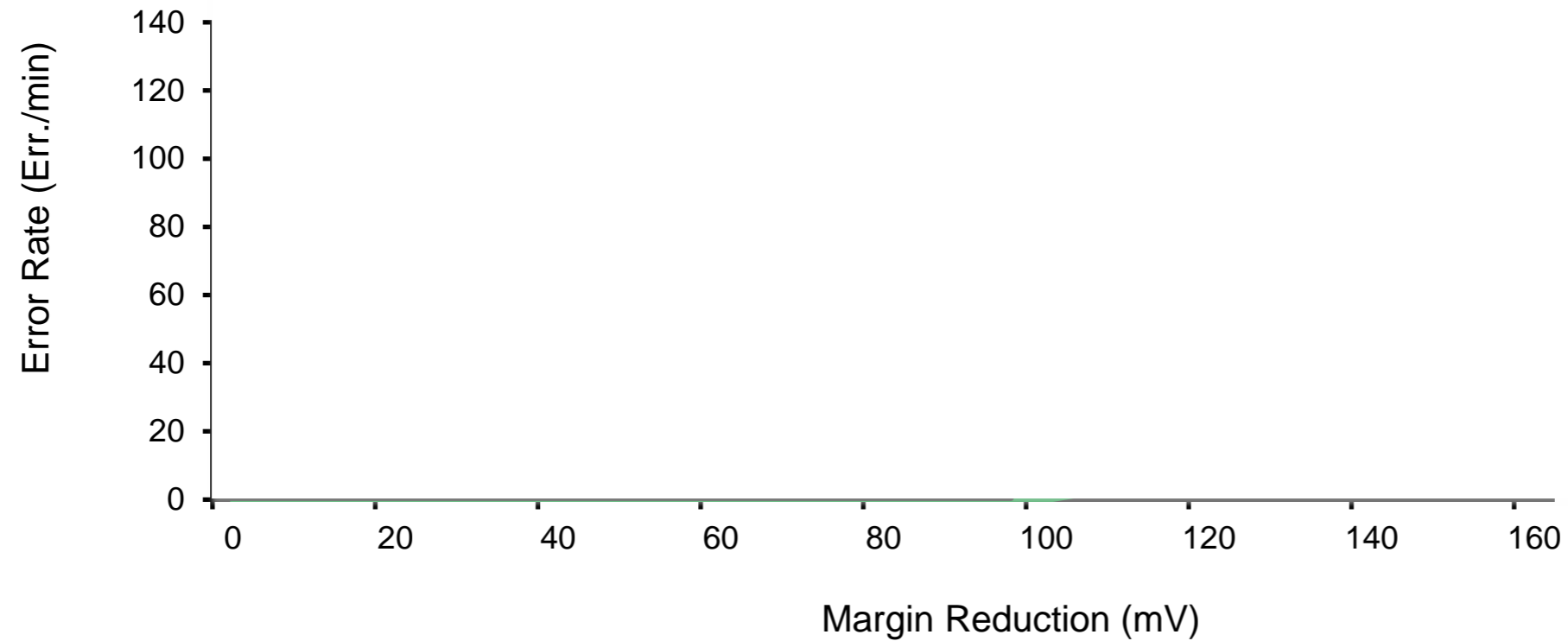
**Margin at low Vdd (200mV)**







# Correctable Errors at Low Voltage



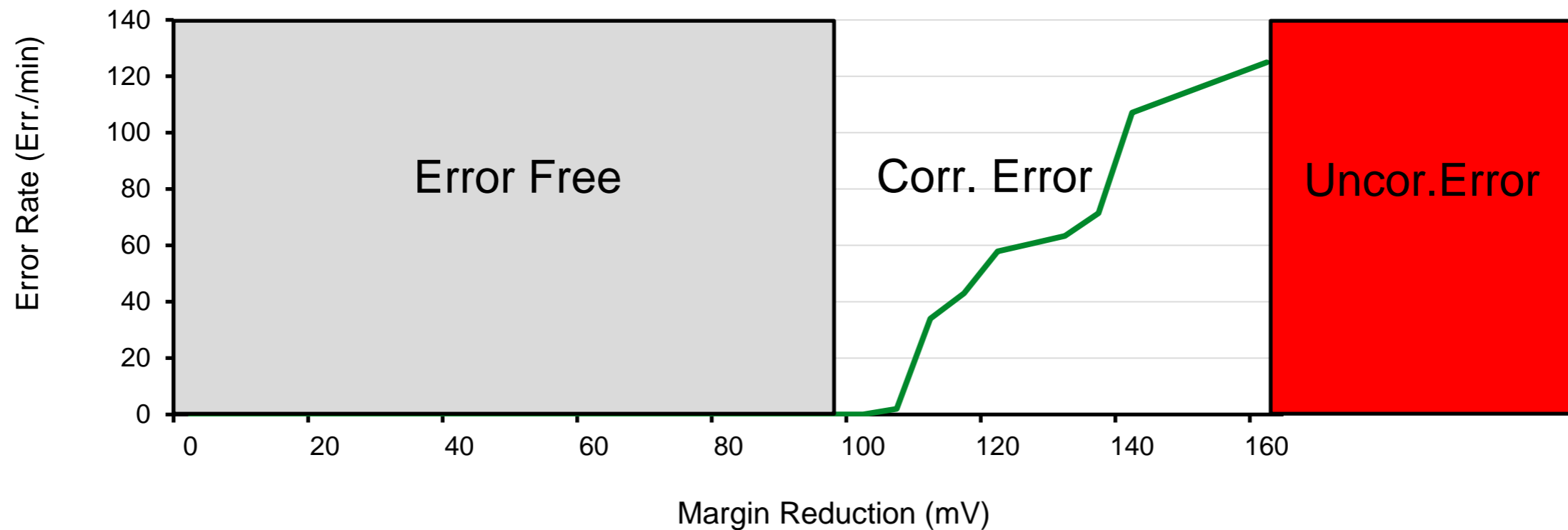


# Correctable Errors at Low Voltage



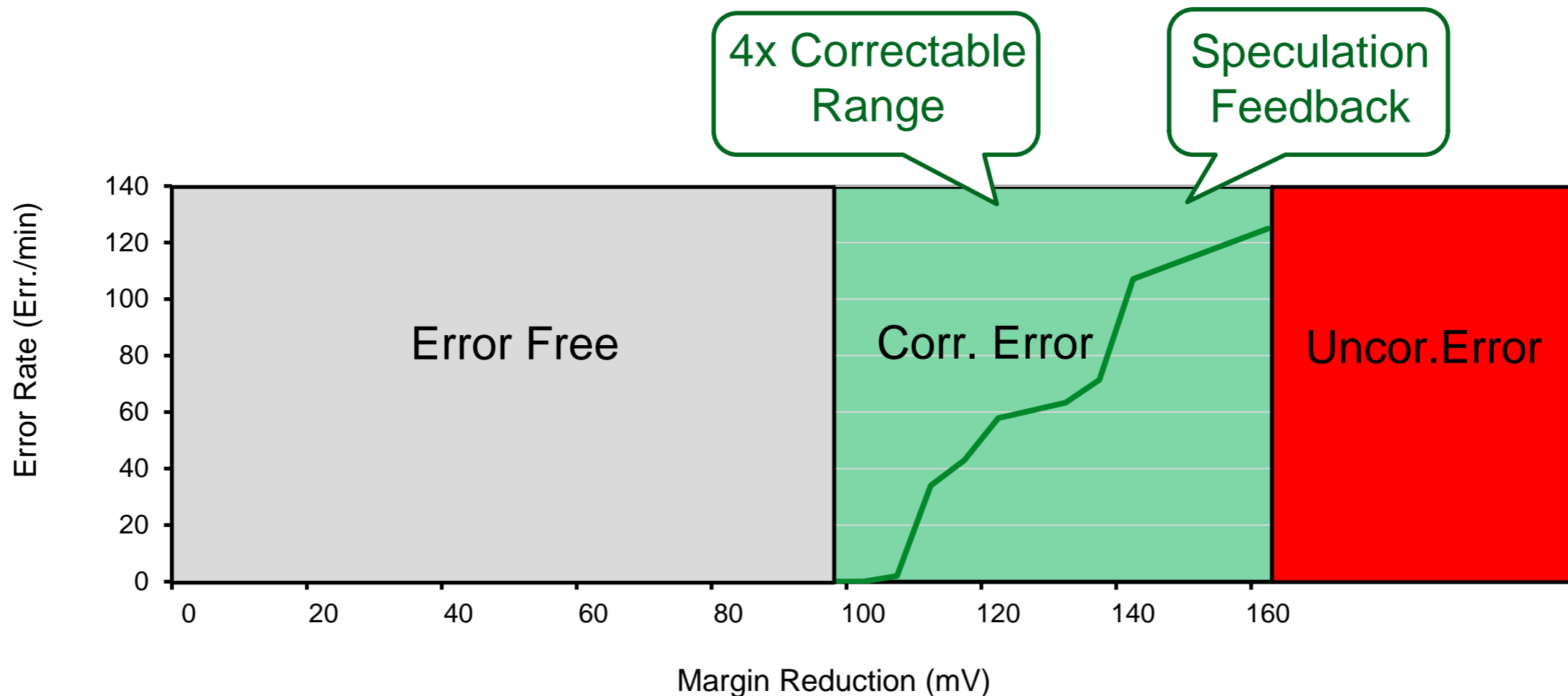


# Correctable Errors at Low Voltage





# Correctable Errors at Low Voltage

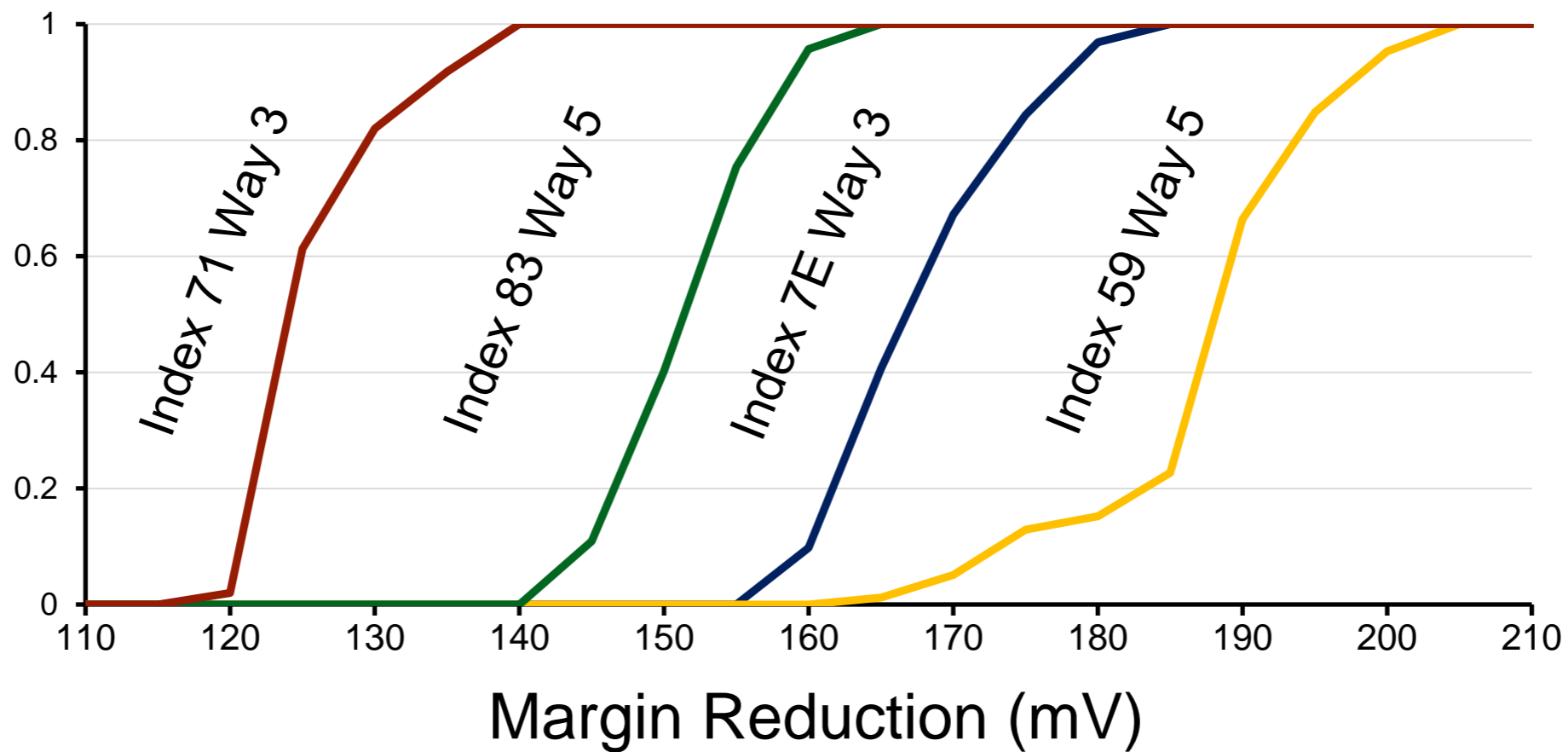


- Large buffer zone for speculation
- Correctable error range is 4x relative to high Vdd



# Predictability of Select Cache Lines

Probability of Corr. Errors



Select cache lines consistently react to  $V_{dd}$  reduction



# Outline

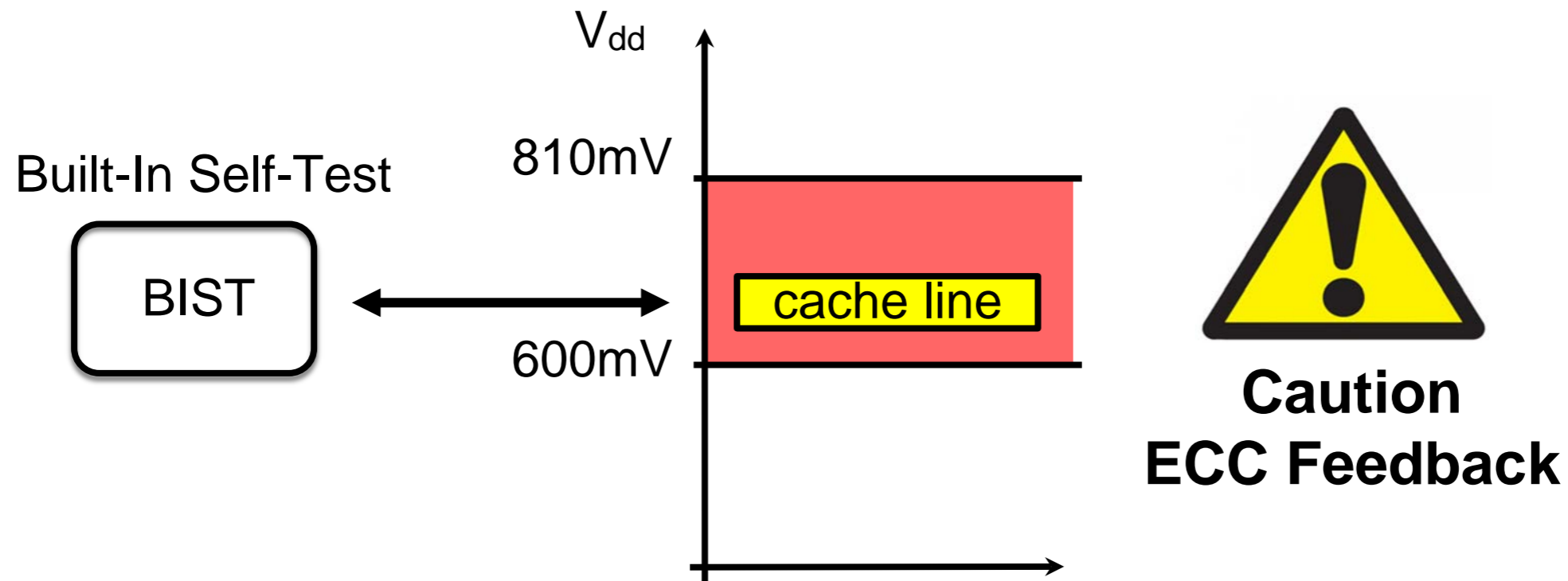
- Motivation
- **ECC-based voltage speculation**
- Experimental framework
- Evaluation





# ECC Guided Voltage Speculation

- Main idea:
  - Dynamically lower  $V_{dd}$  at constant frequency
  - Treat correctable errors as “early warning system”





# ECC Guided Voltage Speculation

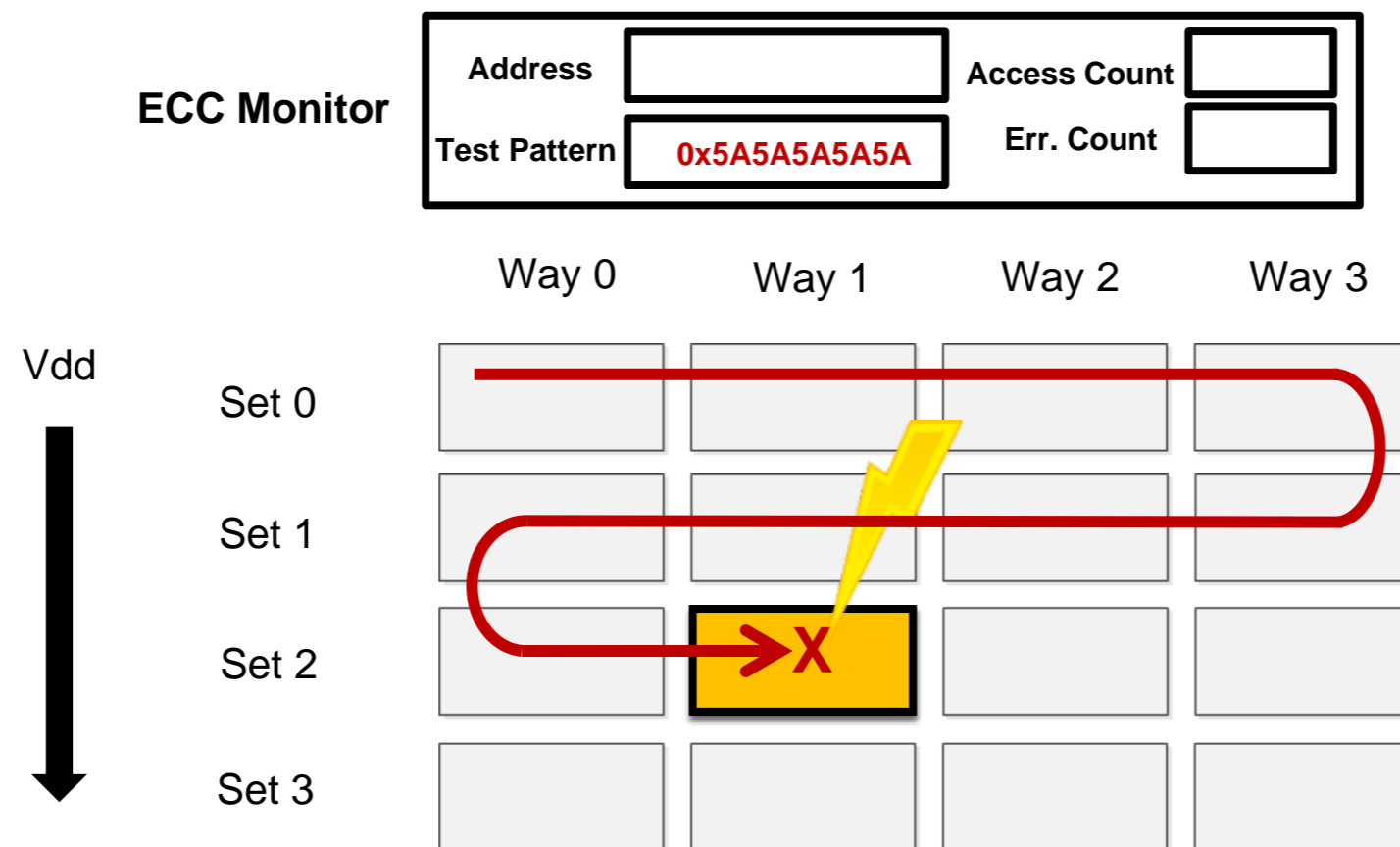
Continuous monitoring of weakest cache line



# ECC Guided Voltage Speculation

Continuous monitoring of weakest cache line

## Discovery Phase

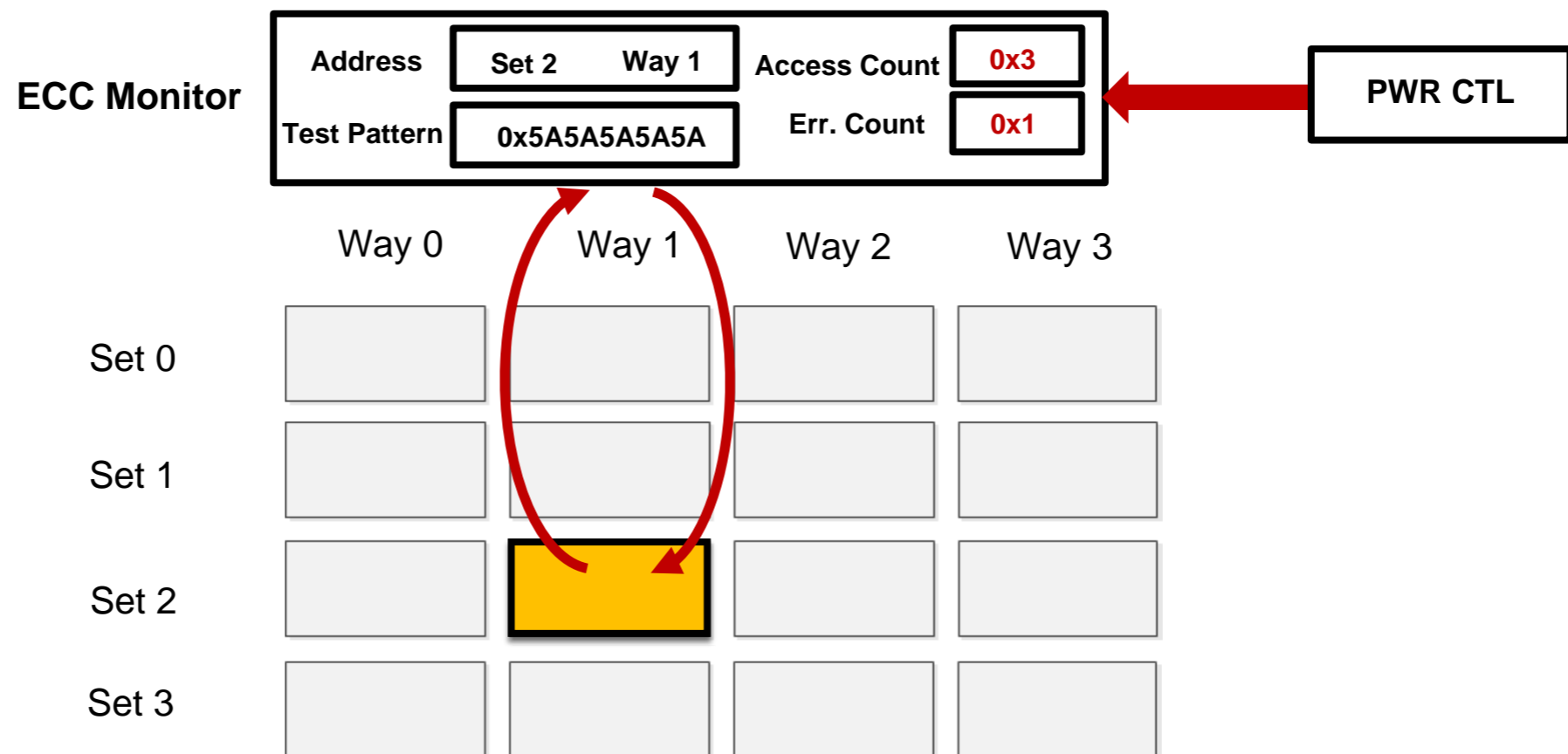




# ECC Guided Voltage Speculation

Continuous monitoring of weakest cache line

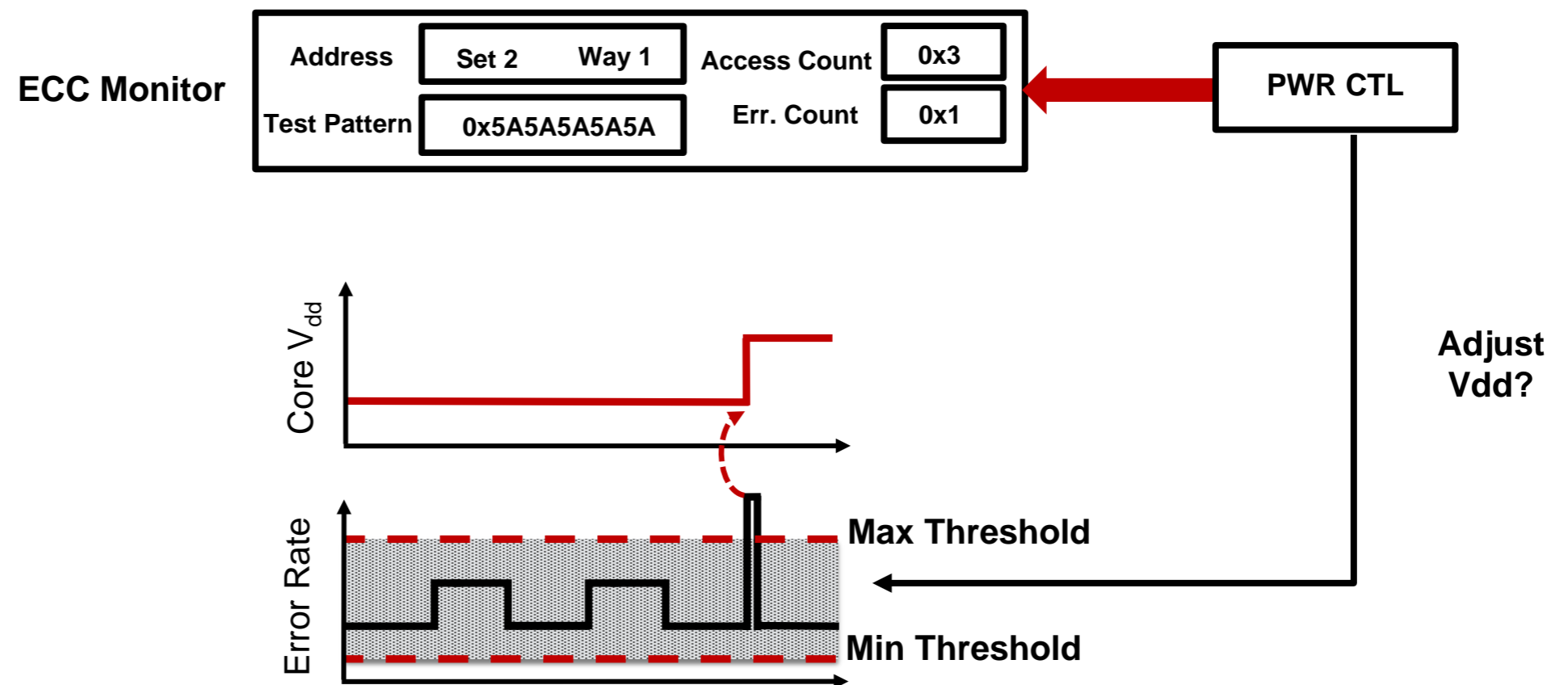
## Runtime Phase





# ECC Guided Voltage Speculation

Continuous monitoring of weakest cache line

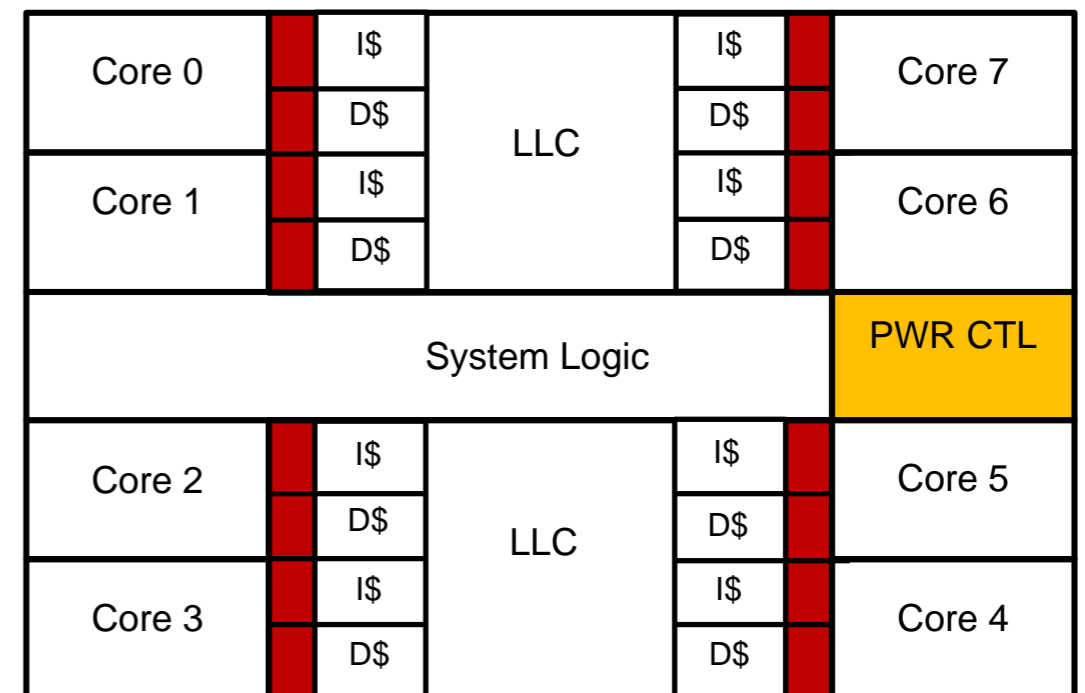




# ECC Monitors and Activation

- ECC monitors to probe vulnerable cache lines

 ECC Monitor



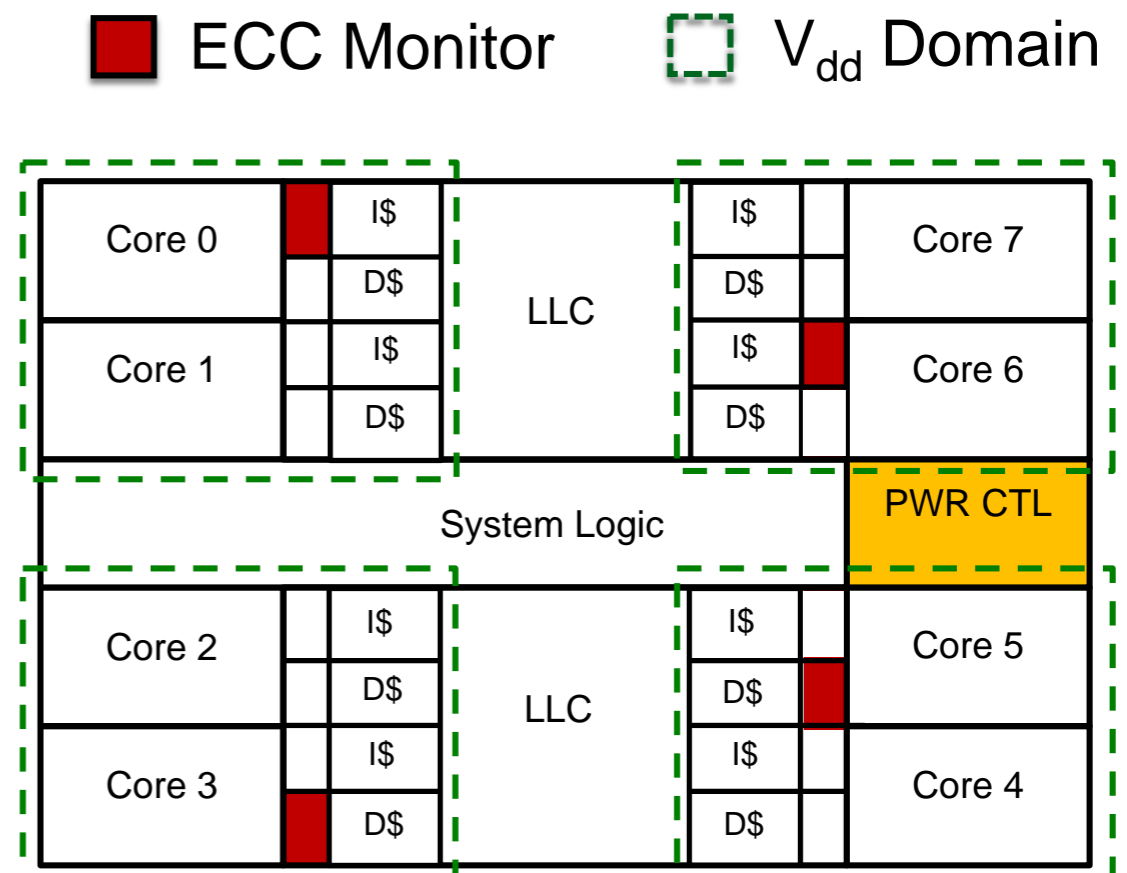
8-core CMP with ECC monitors





# ECC Monitors and Activation

- ECC monitors to probe vulnerable cache lines
- Activate single monitor across  $V_{dd}$  domain



8-core CMP with ECC monitors



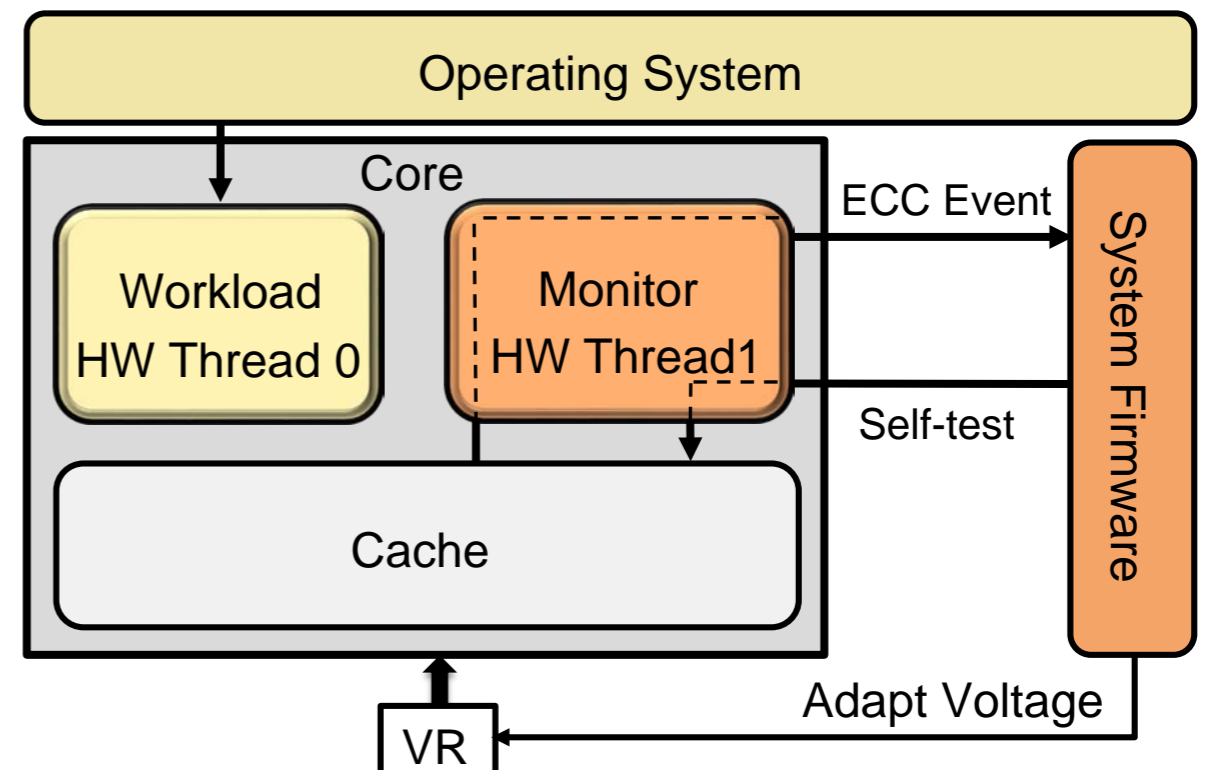
# Outline

- Motivation
- ECC-based voltage speculation
- **Experimental framework**
- Evaluation



# Experimental Framework

- System:
  - BL860c-i4 Integrity Server from HP
  - 2x 9560 Itanium II CPUs
- Simulation (Firmware):
  - HW thread to monitor weak cache line
  - Dedicated “service” core for error logging and power measurements
- Benchmarks:
  - CoreMark, SPEC CPU2000, SPECjbb2005, and stress test application



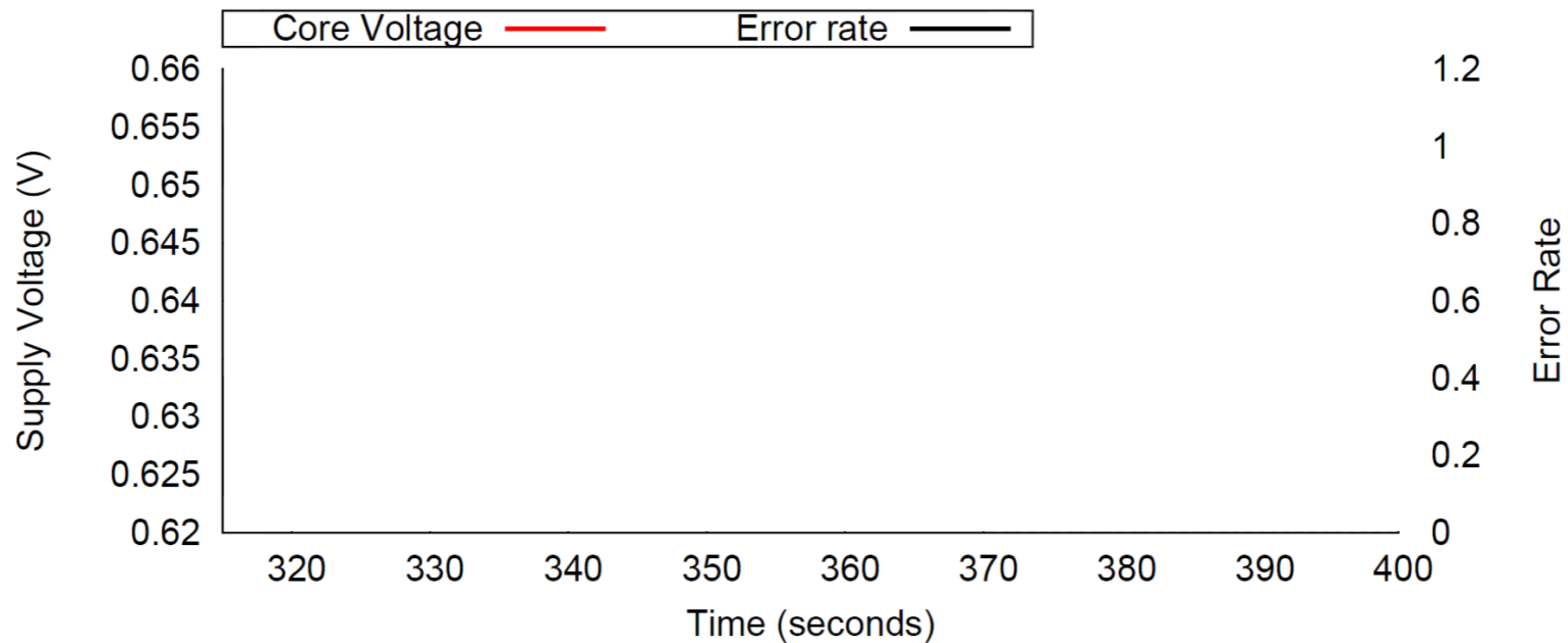


# Outline

- Motivation
- ECC-based voltage speculation
- Experimental framework
- **Evaluation**



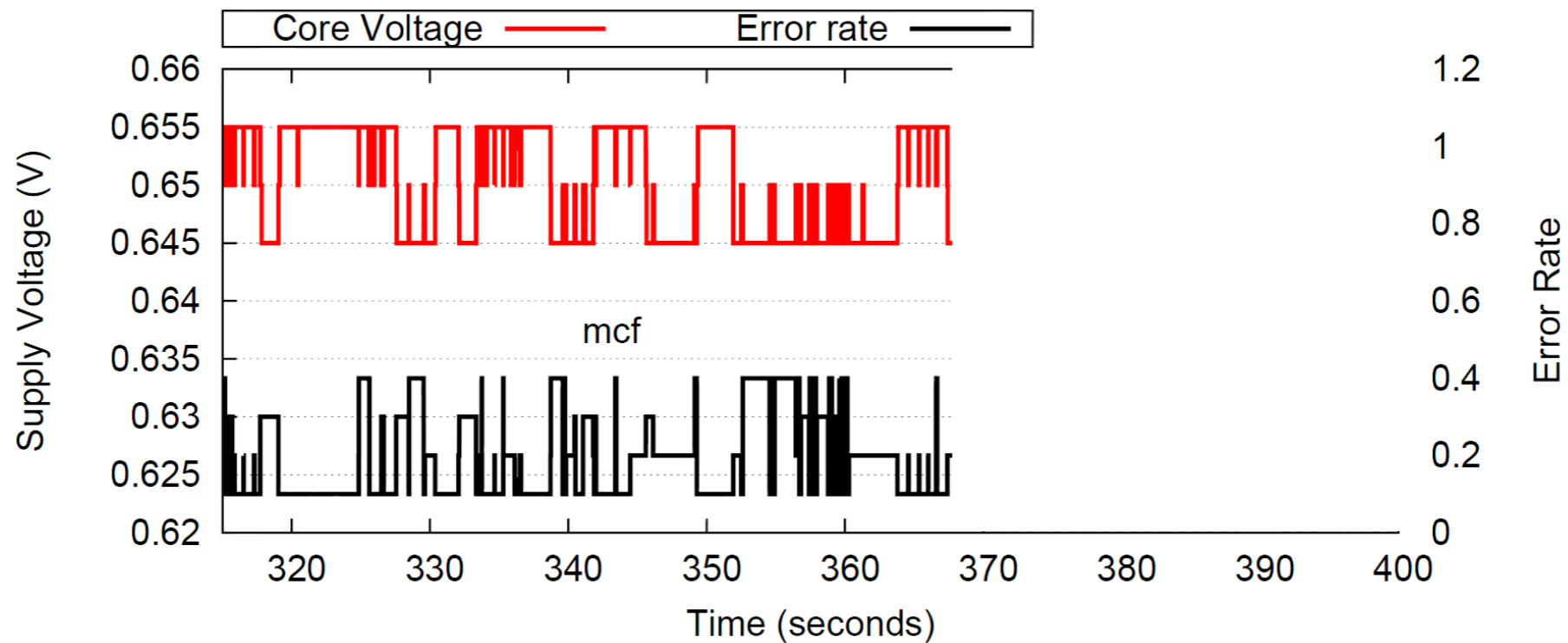
# Voltage Speculation in Action



$V_{dd}$  adapts to changing conditions and context switches using error rate as feedback



# Voltage Speculation in Action

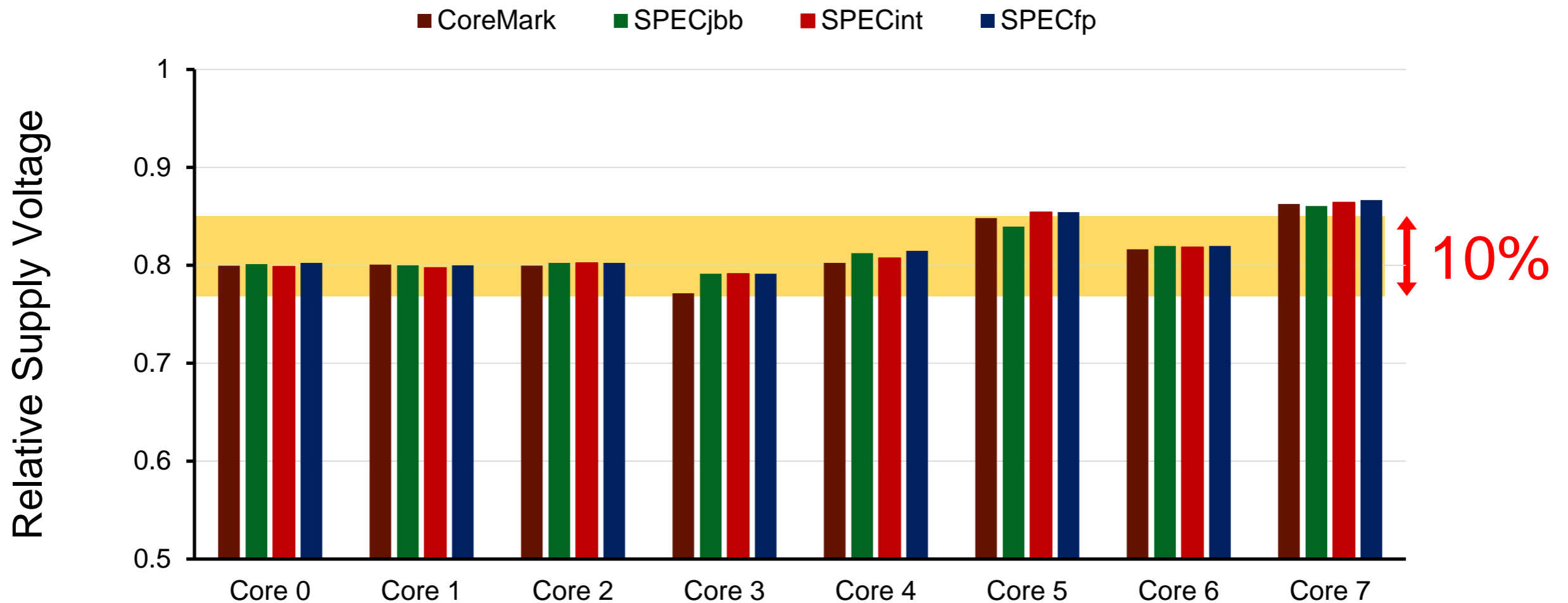


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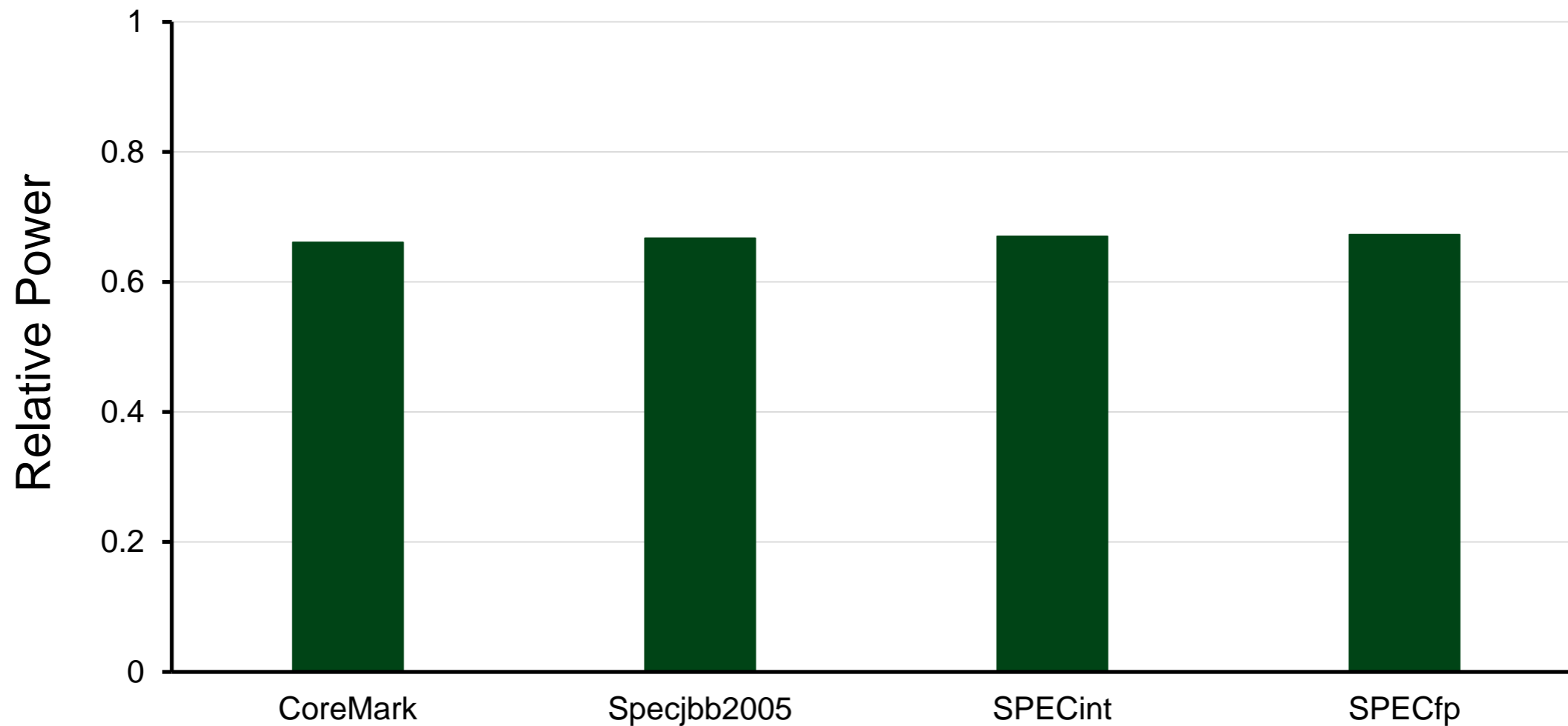
# Supply Voltage Reduction



18% average V<sub>dd</sub> reduction



# Power Savings

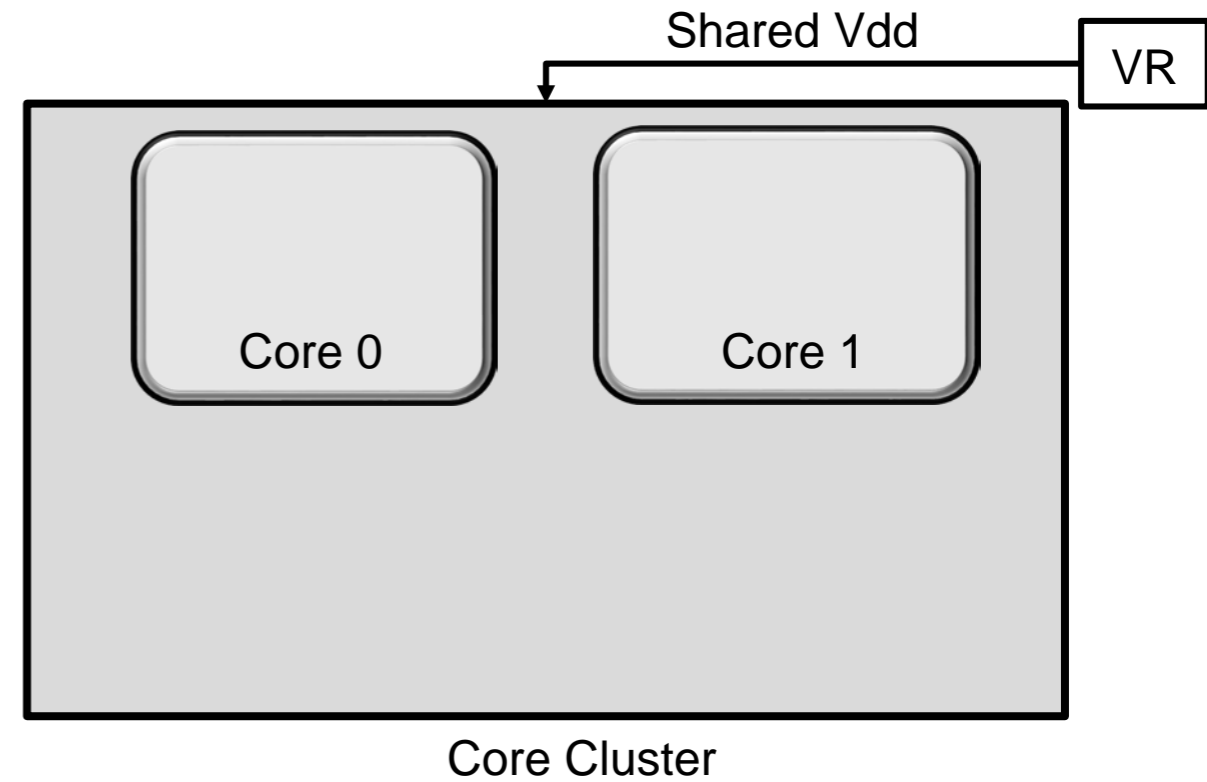


**33% power reduction across all cores**



# Speculation Sensitivity to Workload

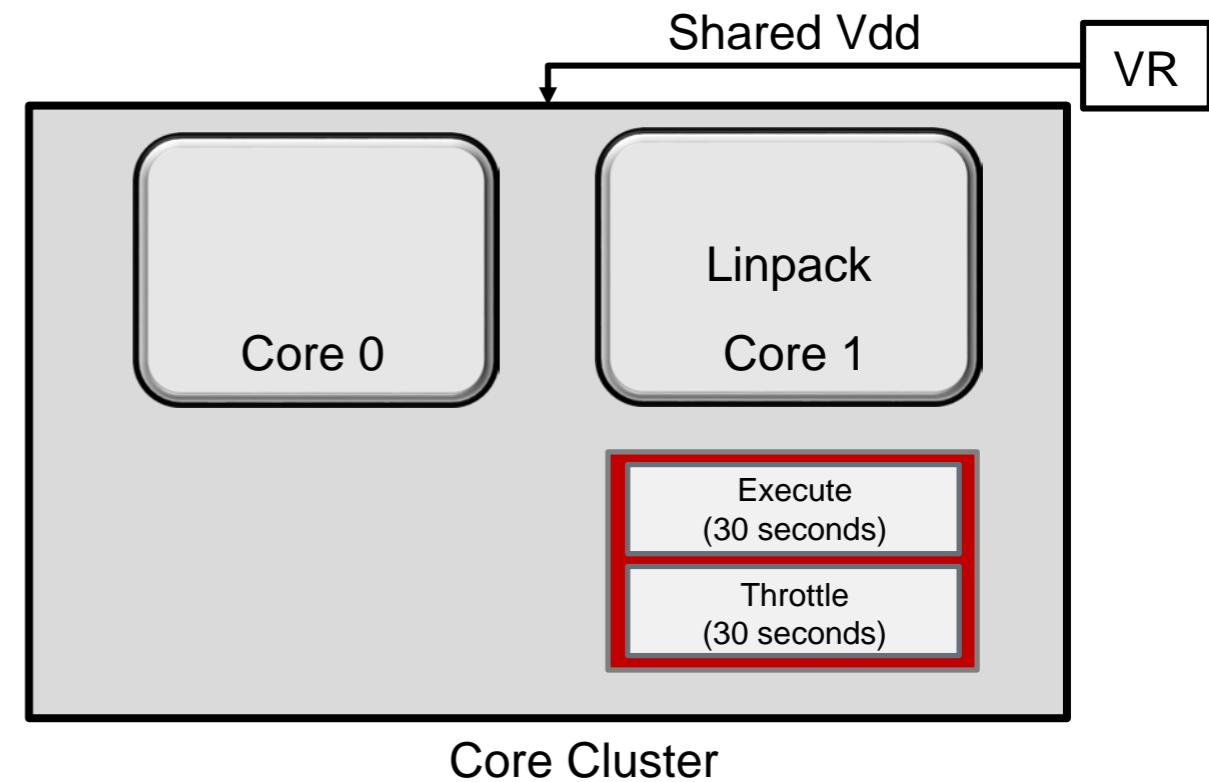
- Exploit auxiliary core within core cluster to stress  $V_{dd}$





# Speculation Sensitivity to Workload

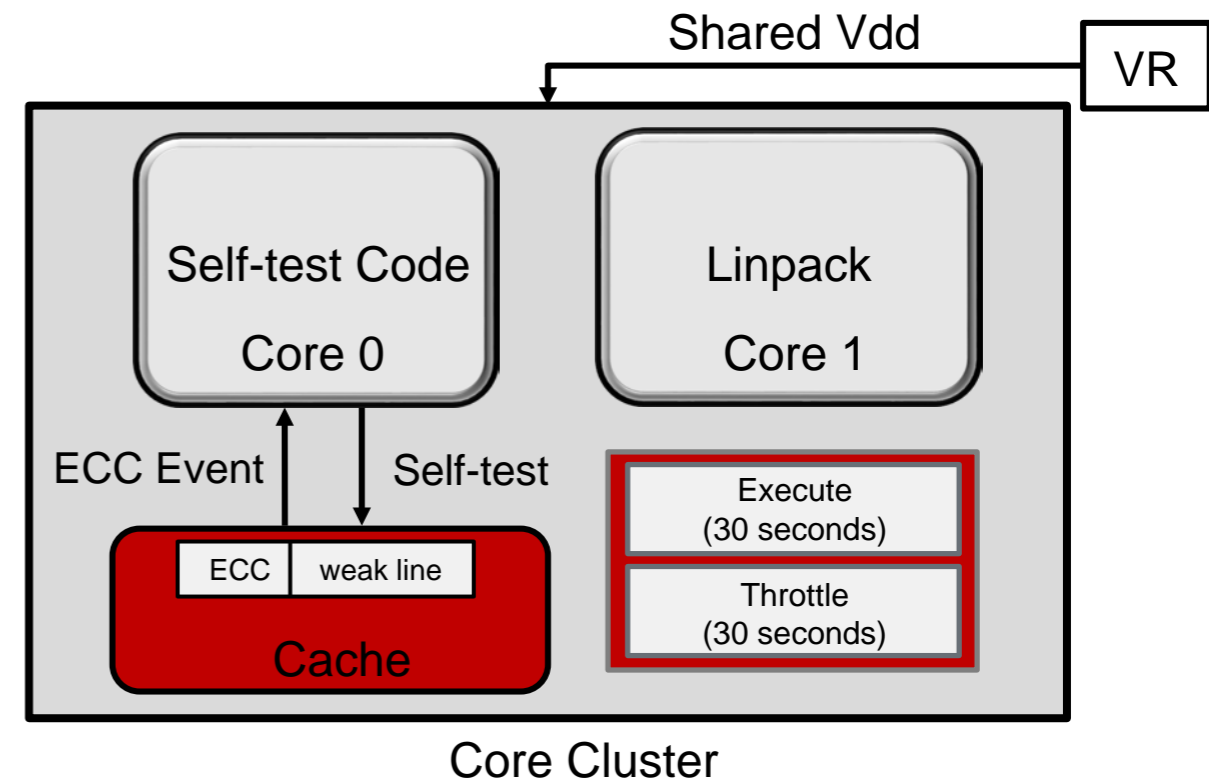
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# Speculation Sensitivity to Workload

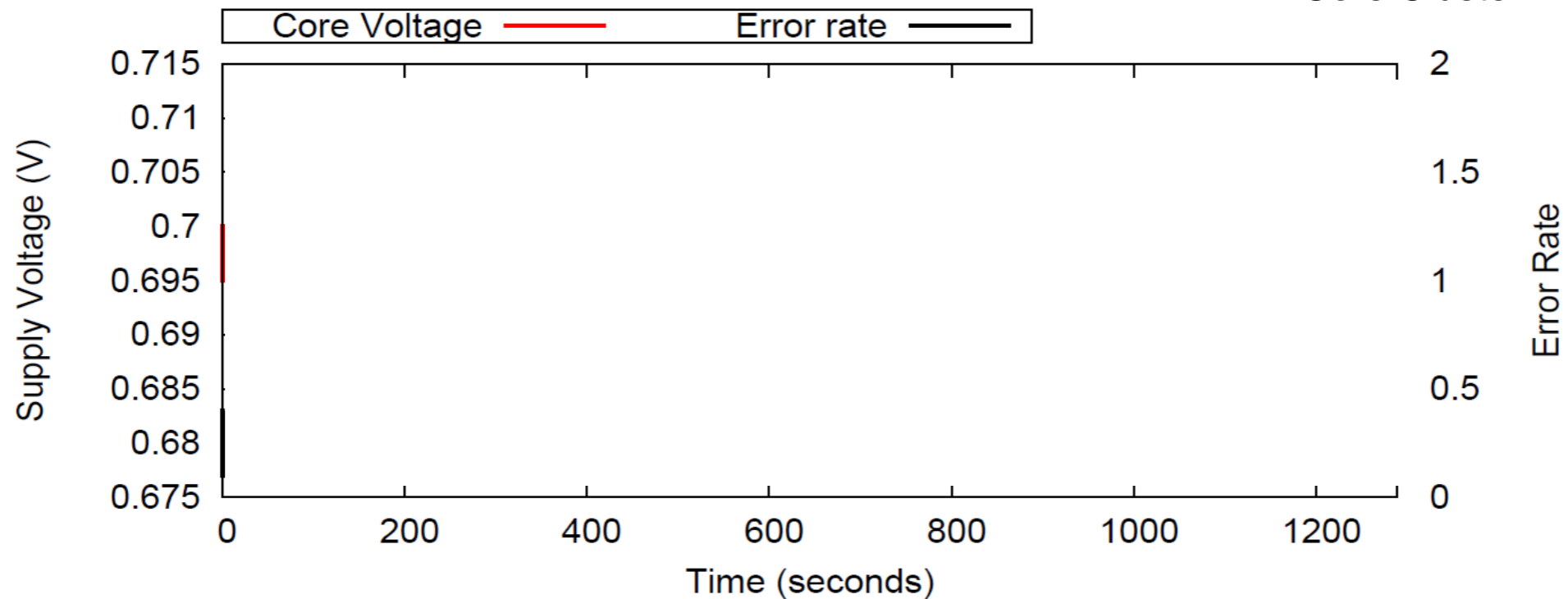
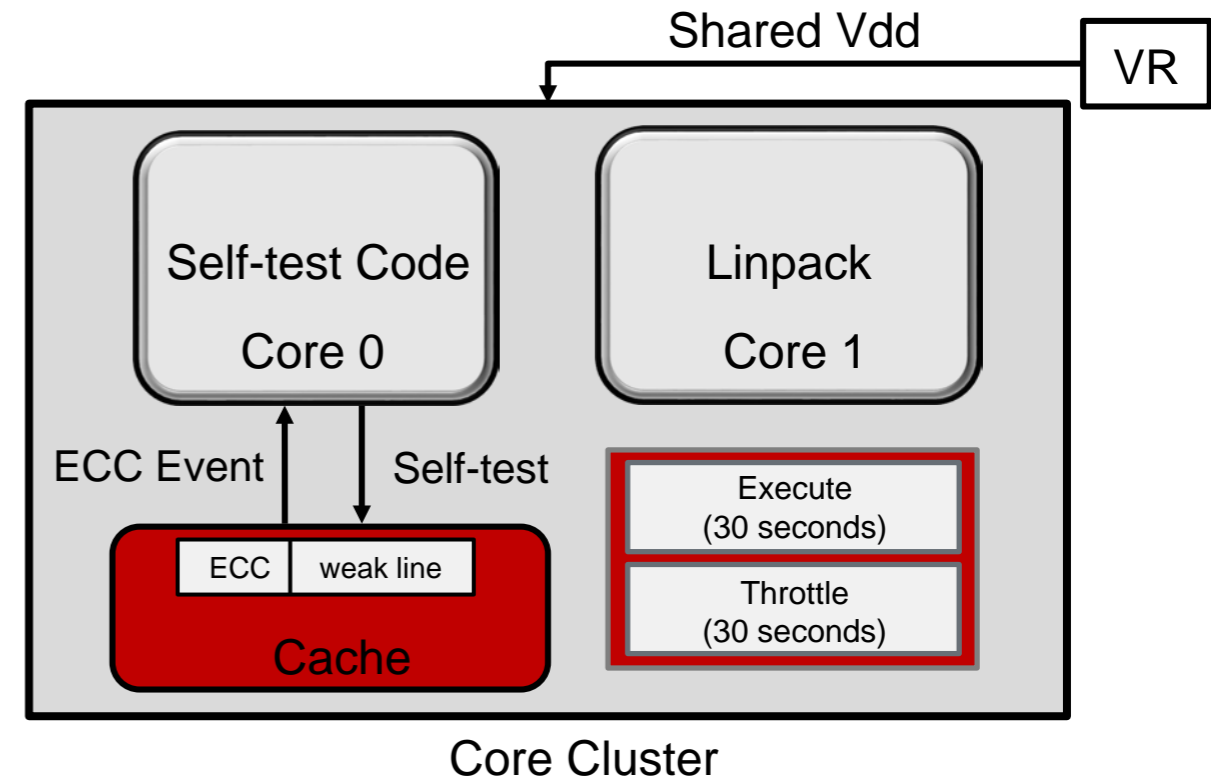
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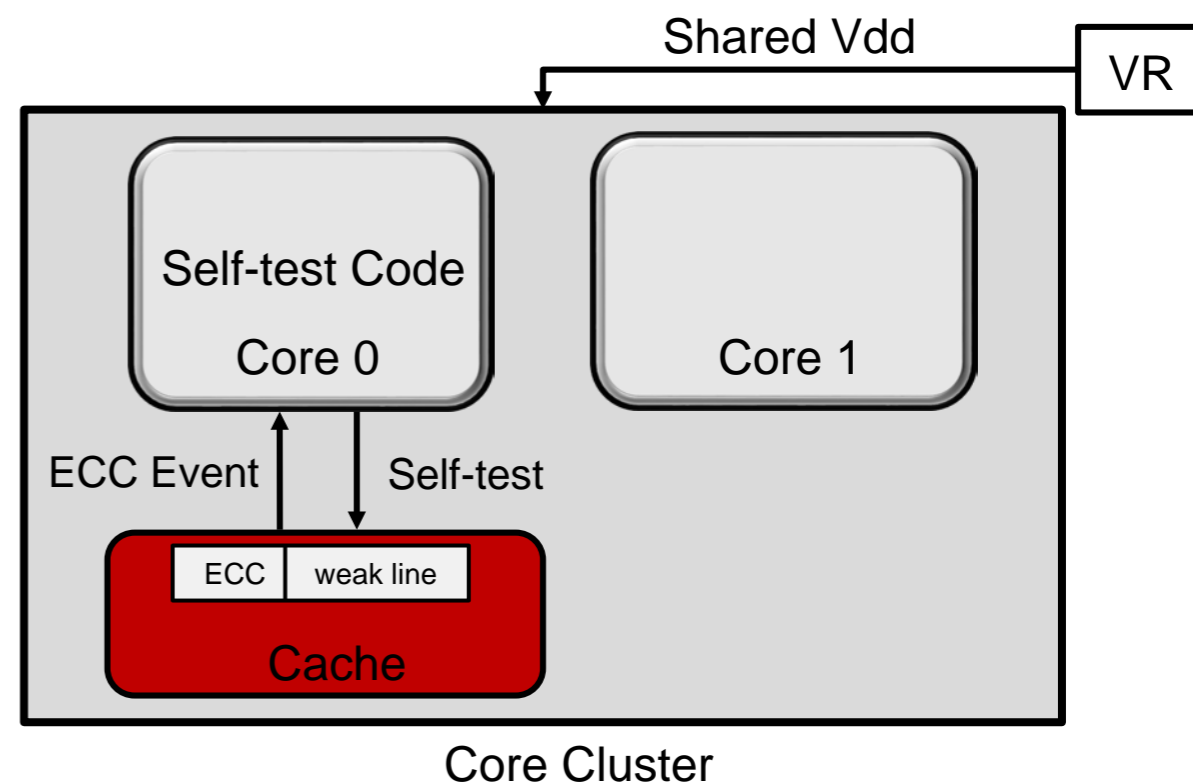
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# Resiliency to Voltage Noise

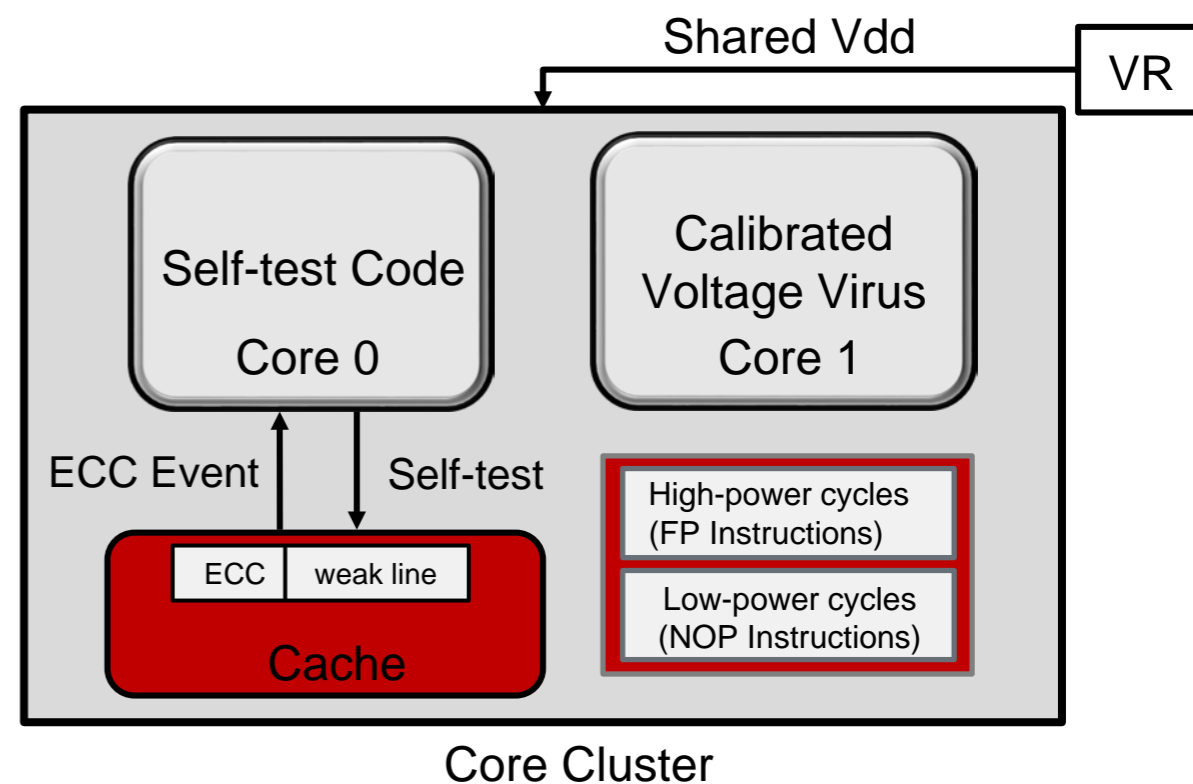
- Similarly exploit auxiliary core within core cluster to induce noise





# Resiliency to Voltage Noise

- Similarly exploit auxiliary core within core cluster to induce noise

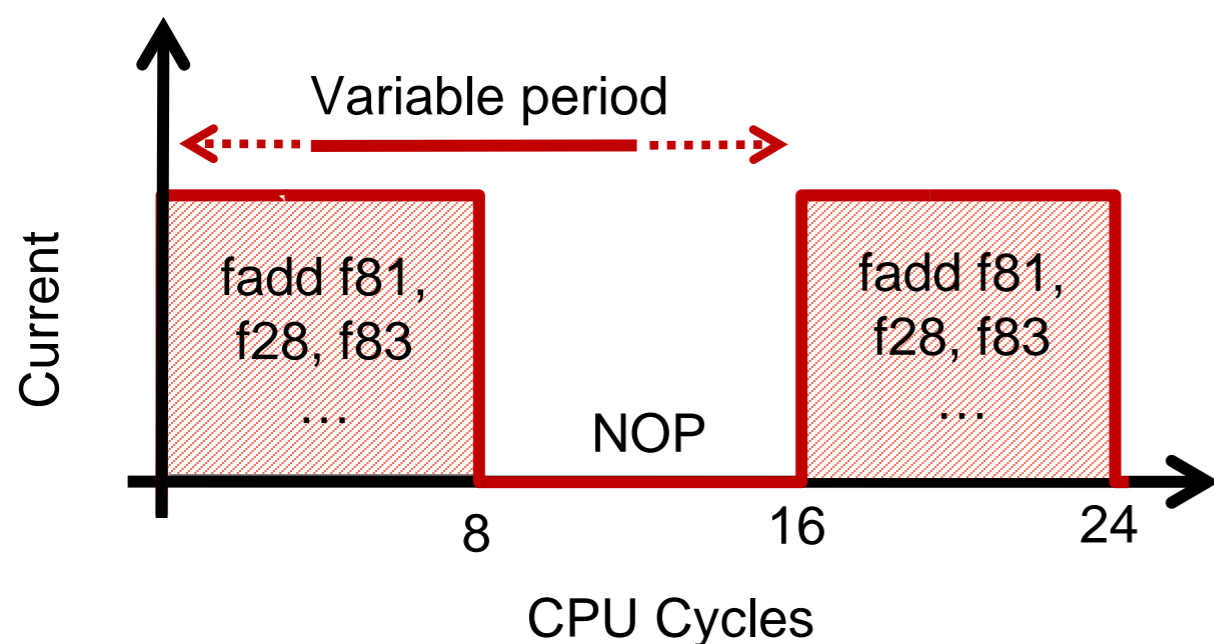
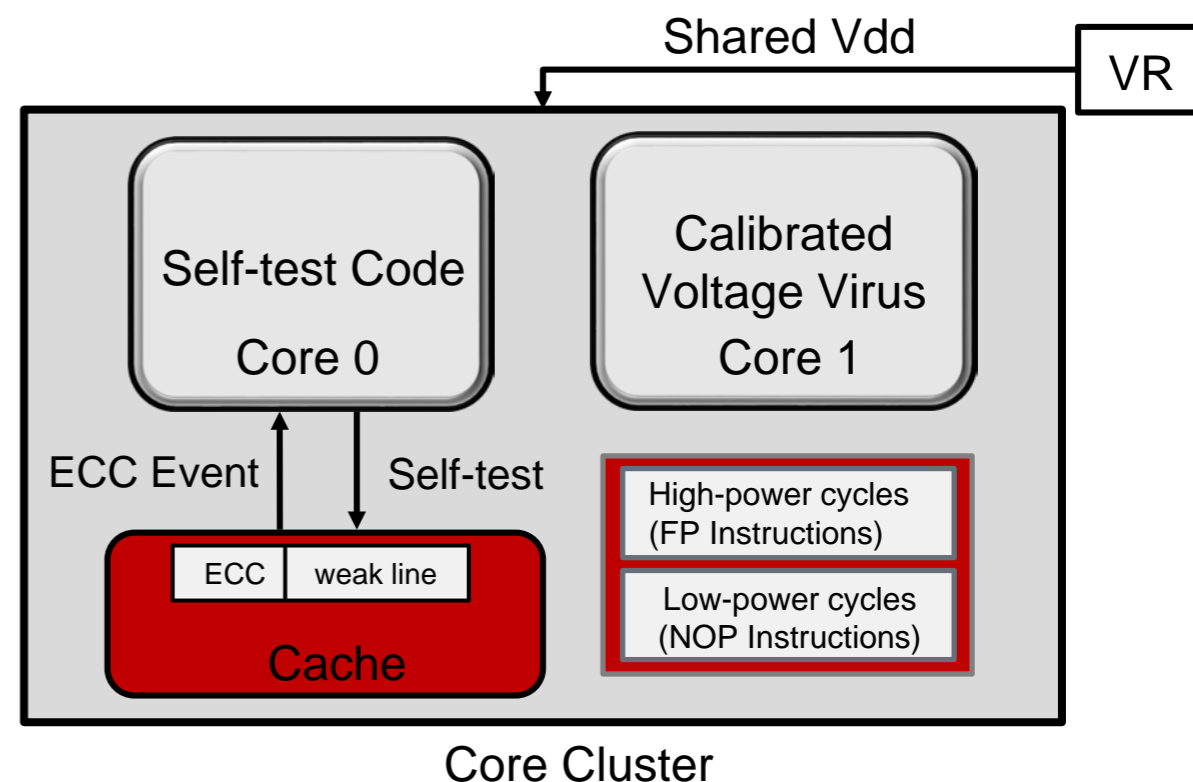






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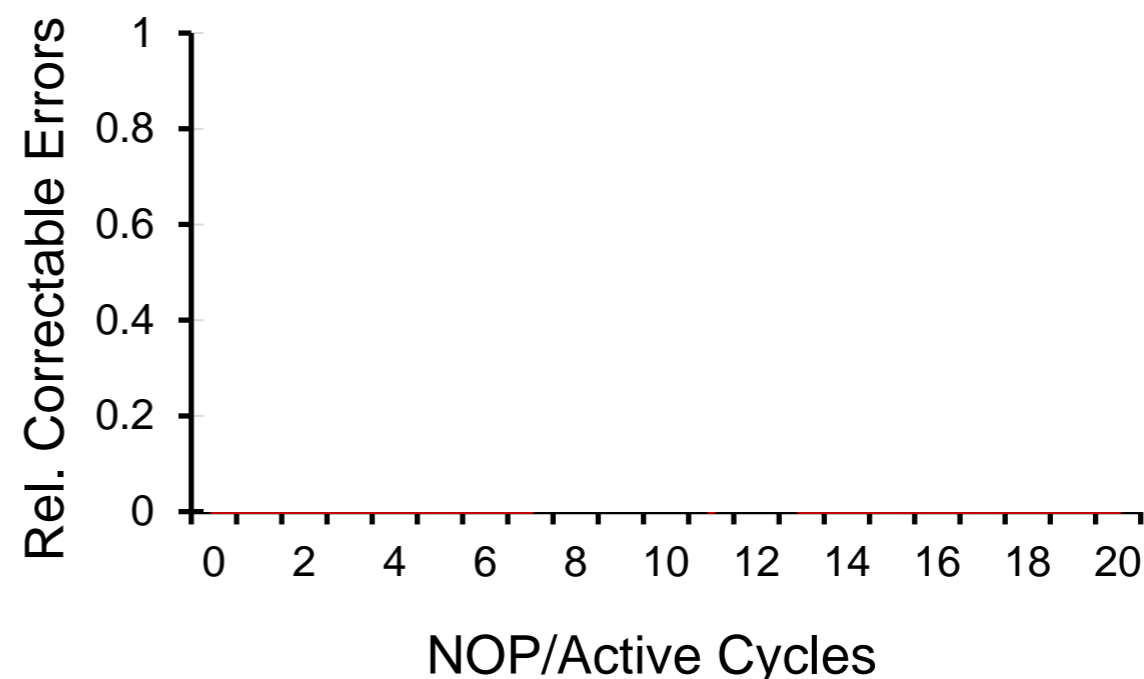
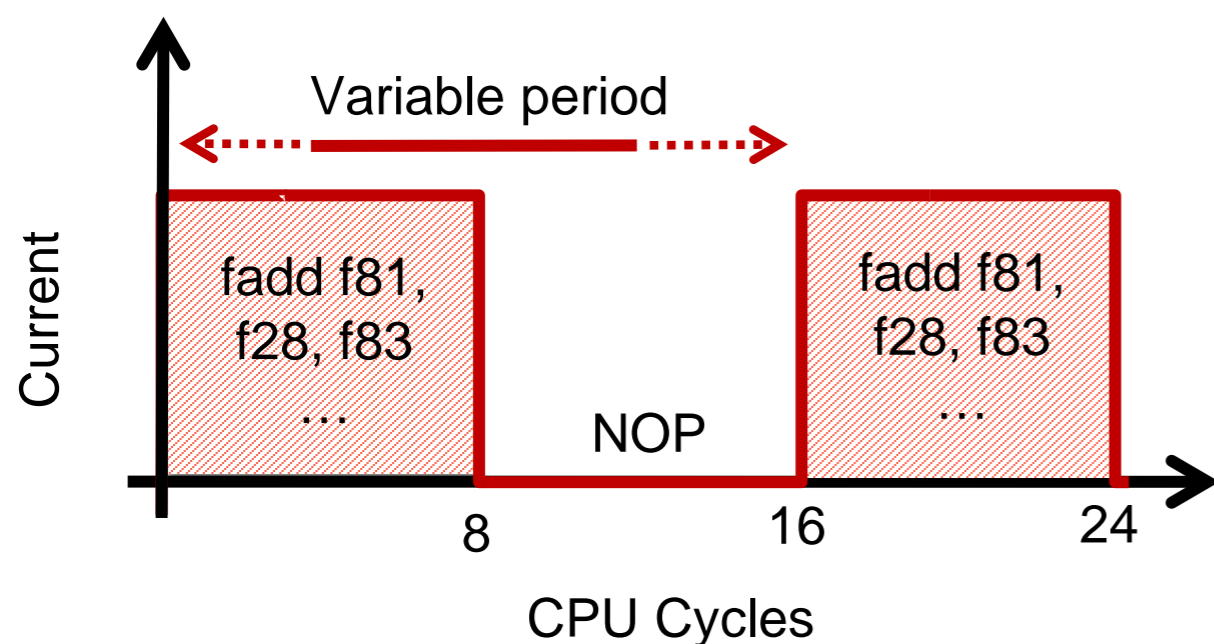
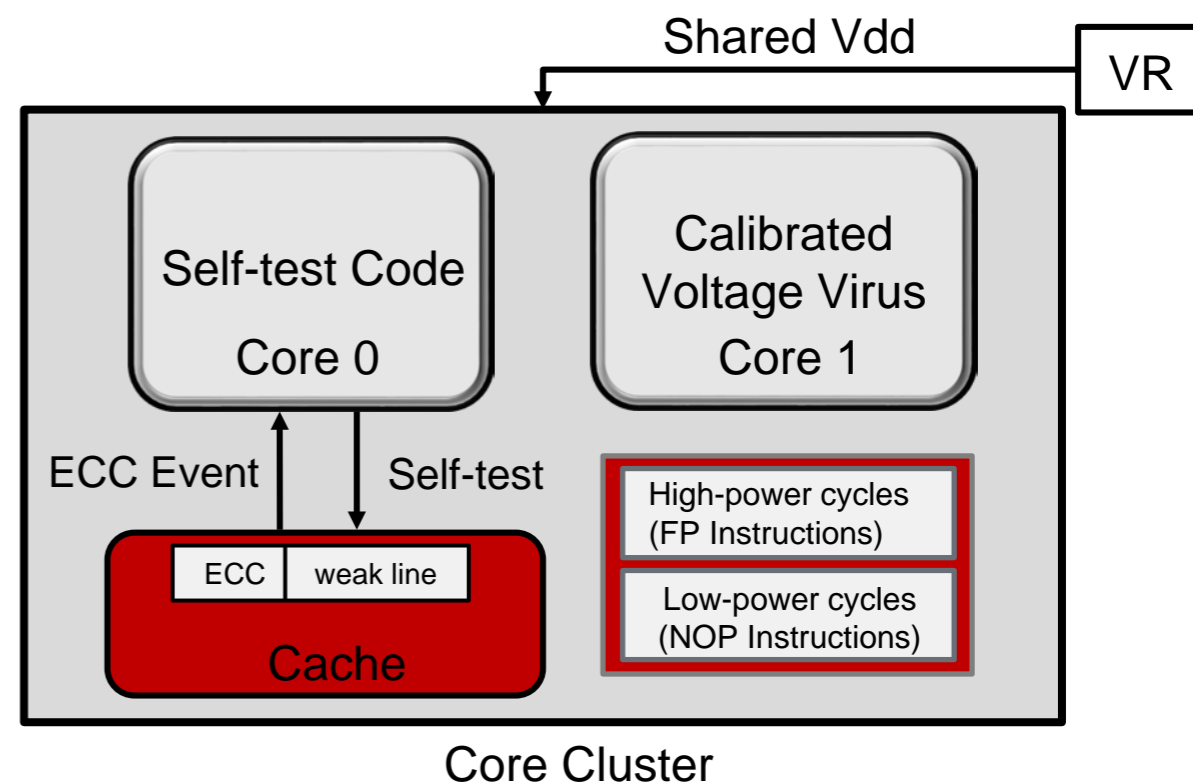
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# Resiliency to Voltage Noise

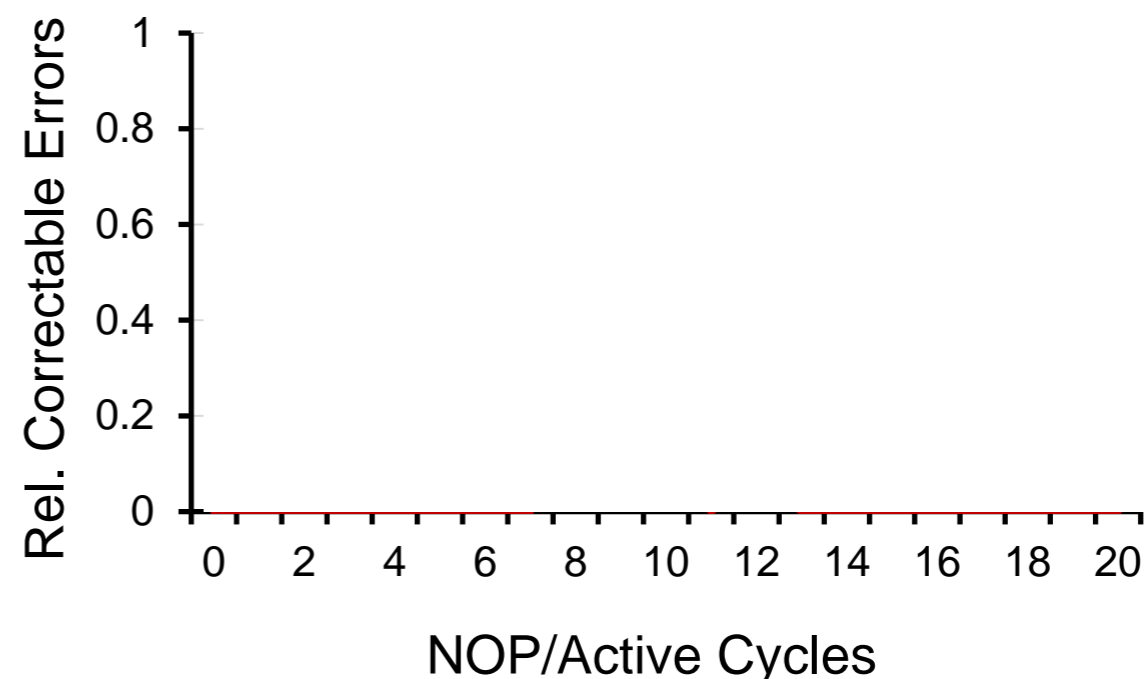
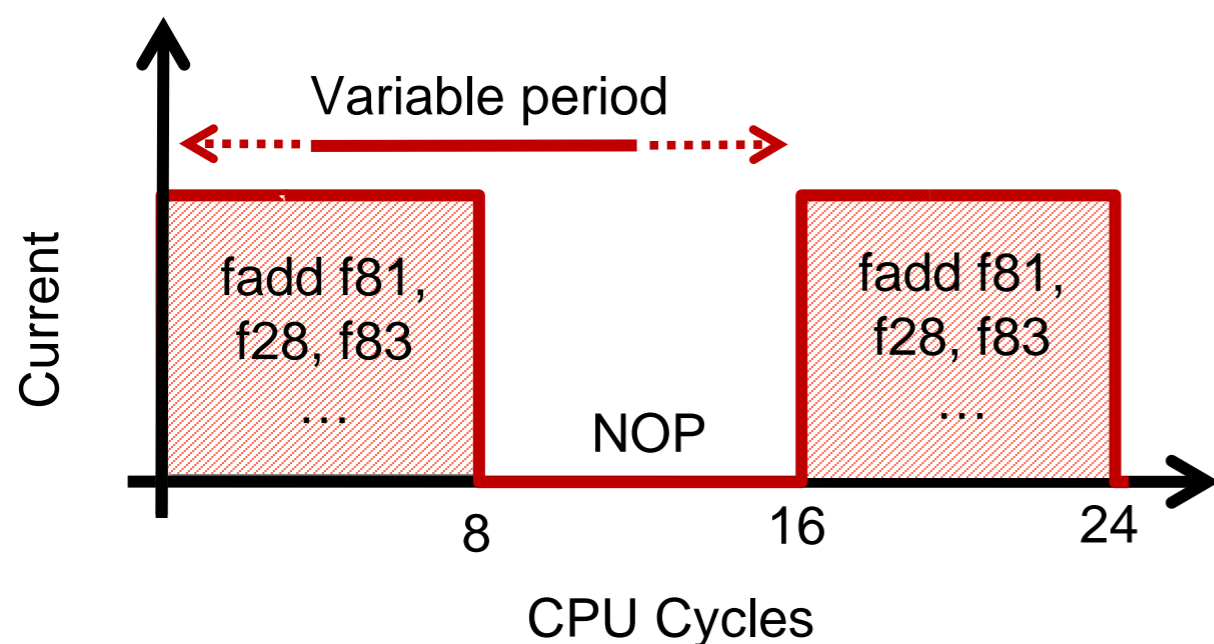
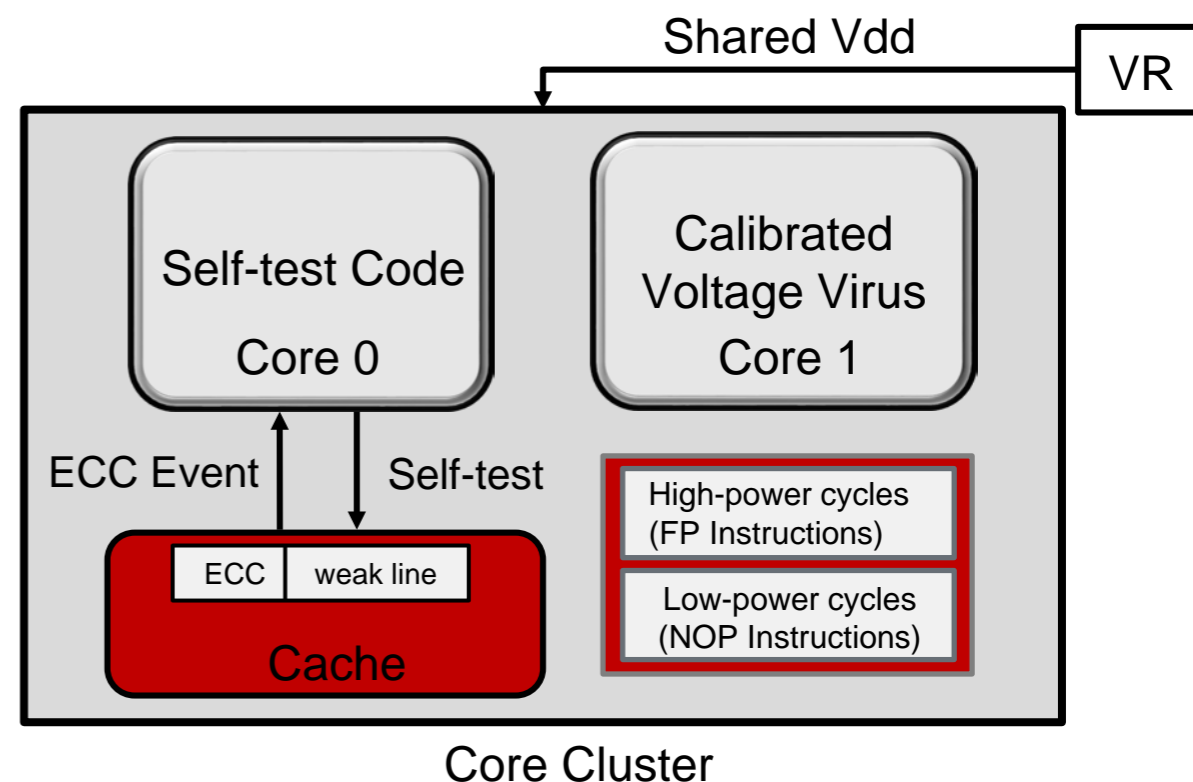
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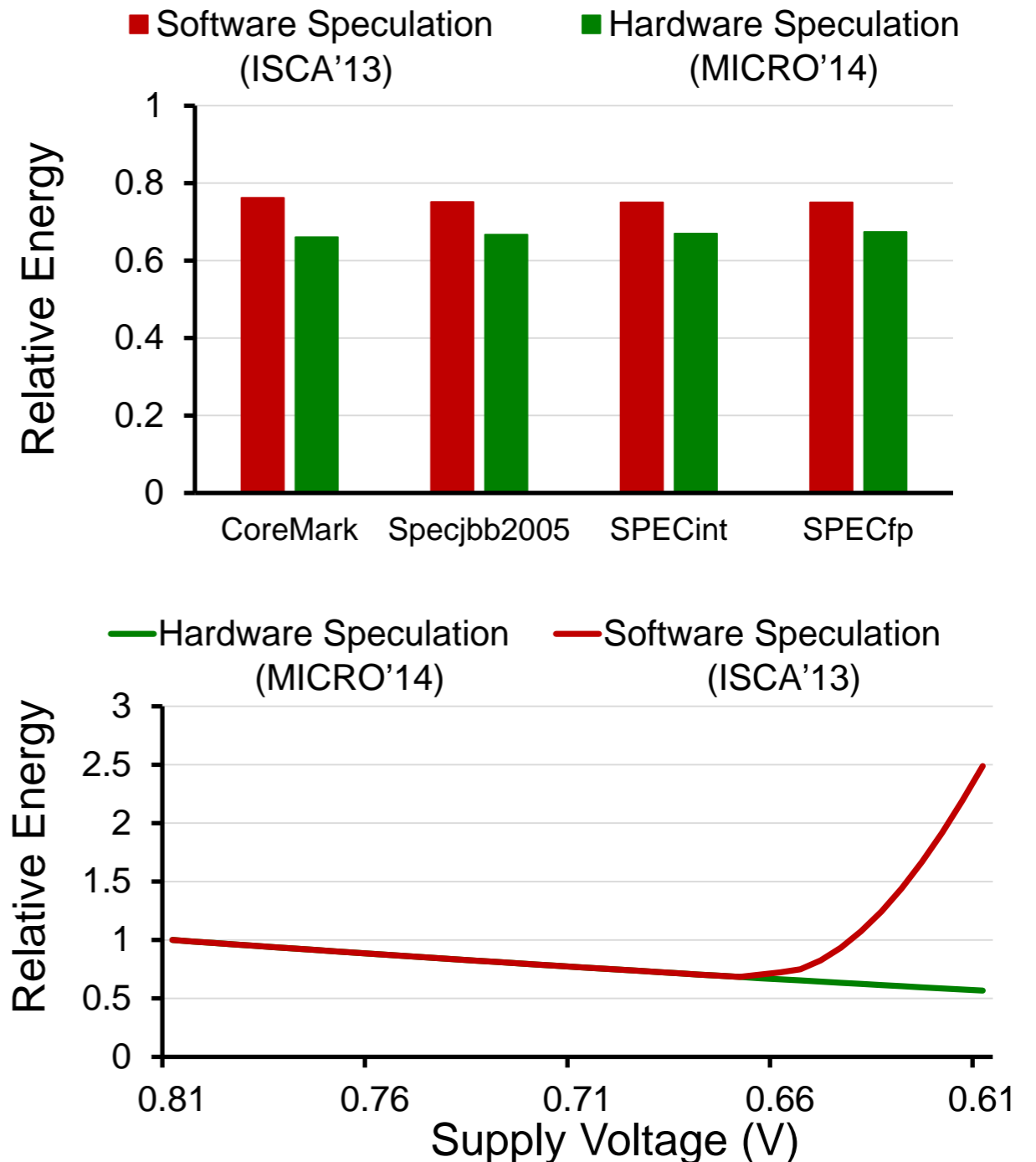
- Similarly exploit auxiliary core within core cluster to induce noise





# Energy Savings

- 33% in energy savings
- 11% improvement in energy efficiency over software speculation approach
- Handling errors at low V<sub>dd</sub> in software is energy inefficient





# Conclusion

- Cache lines can be used for speculation in low voltage
- Demonstrate sensitivity of technique to noise
- Deliver 33% in energy savings
- Evaluate on real system



Thank you!  
Questions?

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